



**RF SAFETY
LAB**

A NEXT GENERATION
TEST LABORATORY™

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Time-Averaging Algorithm Validation Report

FCC ID:	A3LSMS741B
Model (s):	SM-S741B/DS, SM-S741B
Device Type:	Portable Handset
Report Issue Date:	July 11, 2026

Samsung Electronics, Co., Ltd.

129, Samsung-ro, Yeongtong-gu, Suwon-si
Gyeonggi-do, 16677, Rep. of Korea

Certification

The measurement evaluations presented in this report are based on the maximum performance of the tested device(s), which has been shown to be capable of compliance for localized specific absorption rate (SAR) for uncontrolled environment/ general population exposure federal limits in 47CFR § 1.1310 and has been tested in accordance with the measurement procedures specified within this report.

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Steve Liu
President

Table of Contents

1. DUT Specifics.....	3
3. TAS Evaluation Test Cases.....	6
4. Part 2 Test Results.....	8
5. Background on Radiofrequency (RF) Exposure Limits.....	31
6. Technology Specific Test Setup Requirements.....	33
7. Equipment List	49
8. Conclusion.....	50

Appendix A: Verification Plots

Appendix B: System Check

Appendix C: Test Setup Photos

Appendix D: Calibration Certs

1. DUT Specifics

1.1. Time-Averaging Algorithm Verification

This report demonstrates that the DUT, enabled with S.LSI feature for WWAN and Combined-TAS (TAS) time-averaged SAR algorithms and Qualcomm® FastConnect feature for WLAN time-averaged SAR algorithms, is compliant under Tx varying transmission scenarios per S.LSI's and Qualcomm's recommended test plans for WWAN and C-TAS and WLAN respectively. Part 0 and Part 1 test reports complimenting this Time-Averaging Algorithm Validation Report are necessary for a comprehensive RF Exposure evaluation.

1.2. Device under Test

The manufacturer has confirmed that the device is within operational tolerances expected for production units and has the same physical, mechanical, and thermal characteristics expected for production units. The serial number of the device used for each test is indicated alongside the results.

1.3. Time-Averaging Algorithm for RF Exposure Compliance

This device is enabled with the S.LSI and FastConnect feature. This feature implements a time-averaging algorithm in real time to control and manage transmitting power and ensure the time-averaged RF exposure is in compliance with FCC requirements all the time.

Note that Bluetooth and NFC operations are not enabled with any time averaging algorithms for this device.

The time-averaging algorithms maintain the time-averaged transmit power, in turn, time-averaged RF exposure of SAR_design_target, below the predefined time-averaged power limit (i.e., Plimit for sub-6 radio), for each characterized technology and band. Characterization is achieved by determining Plimit for WWAN sub-6/WLAN that corresponds to the exposure design targets after accounting for all device design related uncertainties. The SAR characterization is denoted as SAR Char in this report.

The time-averaging algorithms allow the device to transmit at higher power instantaneously, as high as Pmax, when needed, but enforces power limiting to maintain time-averaged transmit power to Plimit. Below table shows Plimit settings and maximum tune up output power Pmax configured for this EUT for various transmit conditions (Device State Index DSI & RSI).

Table 1-1
SAR Design Calculations

SAR_design_target			
$SAR_design_target < SAR_regulatory_limit \times 10^{\frac{-Total\ Uncertainty}{10}}$			
1g SAR		10g SAR	
Total Uncertainty	1.0 dB	Total Uncertainty	1.0 dB
SAR_regulatory_limit	1.6 W/kg	SAR_regulatory_limit	4.0 W/kg
SAR_design_target	1.0 W/kg	SAR_design_target	2.5 W/kg

Table 1-2
DSI & RSI Descriptions

Scenario	Description	SAR Test Cases
Head (DSI = 1) for FastConnect (RSI = 1) for S.LSI	_ Device positioned next to ear _ Receiver Active	Head SAR per KDB Publication 648474 D04
Body-worn (DSI = 0) for FastConnect (RSI = 0) for S.LSI	_ Device being used with a body-worn accessory	Body-worn SAR per KDB Publication 648474 D04
Hotspot (DSI = 0) for FastConnect (RSI = 0) for S.LSI	_ Device transmits in hotspot mode near body _ Hotspot Mode Active	Hotspot SAR per KDB Publication 941225 D06
Phablet (DSI = 0) for FastConnect (RSI = 0) for S.LSI	_ Device is held to hand	Phablet SAR per KDB Publication 648474 D04 & KDB Publication 616217 D04

1.4. Time-Averaging Algorithm

Technical description includes detailed information regarding the implementation of the time-averaging algorithm and parameters used for this device.

1.5. Time-Averaging Algorithm Implementation

For this device, all WWAN technologies are enabled with S.LSI and WLAN technology is enabled with Qualcomm® FastConnect time-averaging algorithm. The Combined Time Averaged SAR (C-TAS) algorithm controls the simultaneous output power of WWAN and WLAN while maintaining compliance with Total Exposure Ratio (TER). NFC and Bluetooth technologies are not controlled by any time-averaging algorithms.

Tables showing the Plimit implemented for this device are found in the Part 0 SAR Report.

1.6. Antenna Groups

The Samsung S.LSI C-TAS operates based on pre-defined Sub-6 GHz antenna groups (AG). The tx antennas in the device are grouped based on spatial variation of RF exposure distributions, where the RF exposure distributions of one AG may be spatially decoupled from those of another AG through R-Matrix-based decoupling assessment.

An antenna group (AG) is defined as a set of antennas that are located in the same physical region of the device, radiate into the same or highly overlapping SAR hotspot, and cannot be spatially separated for SAR evaluation purposes. Antennas within the same AG are assumed to be fully coupled and are represented by the maximum reported SAR among all antennas in that group.

The R-Matrix off-diagonal elements are defined as 0 (decoupled) or 1 (coupled). Once AG0 and AG1 are demonstrated to be spatially decoupled (off-diagonal = 0), simultaneous transmission evaluation may be performed independently for each AG consistent with the R-Matrix decoupling assessment. The justification for the decoupling of the AG for this device is included in the Part 1 SAR/RF Exposure Report.

$$\text{R-matrix for AG0 and AG1} = \begin{bmatrix} 1 & 0 \\ 0 & 1 \end{bmatrix}$$

1.7. Test Guidance Applied

- IEEE 1528-2013
- FCC KDB Publication 941225 D01v03r01, D05v02r05, D05Av01r02, D06v02r01 (2G/3G/4G and Hotspot)
- FCC KDB Publication 248227 D01v02r02 (SAR Considerations for 802.11 Devices)
- FCC KDB Publication 447498 D04v01 (General SAR Guidance)
- FCC KDB Publication 865664 D01v01r04, D02v01r02 (SAR Measurements up to 6 GHz)

2. TAS Evaluation Test Cases

2.1. Part 2 Test Plan

Table 2-1
Part 2 Test Plan -S.LSI Test Cases

Test Case	LSI TC	Test Scenario (Sub 6)	Tech	Band/Config	Antenna	Part 1 Measured Conducted Power [dBm]	Part 1 Measured SAR [W/kg]	Exposure Condition	Position, Distance	Averaged Pmax [dBm]	Averaged Plimit [dBm]	RSI/DSI	Measured Pmax [dBm]	Measured Plimit [dBm]
1	F_TC01, F_TC02	Time-varying Tx power transmission, Case #1, Case #2	GSM Band #1, Test Seq 1	GPRS 1900, 2 Tx Slots	A	15.92	0.555	Body-Worn	Back Side, 5 mm	20.32	16.32	0	20.144	16.921
2			GSM Band #1, Test Seq 2	GPRS 1900, 2 Tx Slots	A	15.92	0.555	Body-Worn	Back Side, 5 mm	20.32	16.32	0	20.144	16.921
3			UMTS Band #1, Test Seq 1	UMTS B5	E	19.62	0.601	Body-Worn/Hotspot	Back Side, 5 mm	23	19.5	0	23.255	19.539
4			UMTS Band #1, Test Seq 2	UMTS B5	E	19.62	0.601	Body-Worn/Hotspot	Back Side, 5 mm	23	19.5	0	23.255	19.539
5			LTE Band #1, Test Seq 1	LTE B13	E	18.69	0.296	Body-Worn/Hotspot	Back Side, 5 mm	23.5	19.5	0	24.171	19.37
6			LTE Band #1, Test Seq 2	LTE B13	E	18.69	0.296	Body-Worn/Hotspot	Back Side, 5 mm	23.5	19.5	0	24.171	19.37
7			sub6 NR SA Band #1, Test Seq 1	NR n66 (1, 240) DFT-S-OFDM	A	15.17	0.615	Body-Worn/Hotspot	Back Side, 5 mm	24	16	0	23.964	16.692
8			sub6 NR SA Band #1, Test Seq 2	NR n66 (1, 240) DFT-S-OFDM	A	15.17	0.615	Body-Worn/Hotspot	Back Side, 5 mm	24	16	0	23.964	16.692
9	F_TC03	Change in Call	LTE	LTE B13	A	21.72	0.533	Body-Worn/Hotspot	Back Side, 5 mm	24.5	21.5	0	23.932	20.752
10	F_TC04	RSI Change	UMTS	UMTS B2	A	21.42	0.098	Head	Left Cheek, 0 mm	24	21	1	24.44	21.297
11	F_TC05	Re-selection in call	UMTS	UMTS B2	A	16.58	0.503	Body-Worn/Hotspot	Back Side, 5 mm	24	16	0	24.44	16.249
12	F_TC06	Antenna/Band Switch	LTE	LTE B13	A	21.72	0.533	Body-Worn/Hotspot	Back Side, 5 mm	24.5	21.5	0	23.956	21.667
13	F_TC08	LTE Inter-band ULCA	sub6 NR SA Band	NR n66 (1, 240) DFT-S-OFDM	A	15.17	0.615	Body-Worn/Hotspot	Back Side, 5 mm	24	16	0	23.89	15.57
14	F_TC10	ENDC SAR Exposure Switching	LTE	LTE B13	A	21.72	0.533	Body-Worn/Hotspot	Back Side, 5 mm	24.5	21.5	0	23.829	22.397
15	F_TC11	ENDC NSA Antenna Switching	LTE	LTE B41	B	16.23	0.315	Body-Worn/Hotspot	Back Side, 5 mm	22.01	16	0	21.196	15.466
			Inter-band ULCA	B12	A	21.84	0.613	Body-Worn/Hotspot	Back Side, 5 mm	24.5	21.5	0	24.89	22.4
				B66	A	16.94	0.773	Body-Worn/Hotspot	Back Side, 5 mm	24	16	0	23.92	16.92
				LTE B12	A	21.84	0.613	Body-Worn/Hotspot	Back Side, 5 mm	24.5	21.5	0	24.89	22.4
				NR n66	A	15.17	0.615	Body-Worn/Hotspot	Back Side, 5 mm	24	16	0	24.84	16.57
				LTE B12	A	21.84	0.613	Body-Worn/Hotspot	Back Side, 5 mm	24.5	21.5	0	23.7	20.86
				NR n66	A	15.17	0.615	Body-Worn/Hotspot	Back Side, 5 mm	24	16	0	24.27	15.09
				NR n77	F	14.72	0.596	Body-Worn/Hotspot	Back Side, 5 mm	26.5	14	0	26.12	13.14

Table 2-2
Part 2 Test Plan -FastConnect Test Cases

Test Case	Test Scenario (Sub 6)	Tech	Band/Config	Antenna	Part 1 Measured Conducted Power [dBm]	Part 1 Measured SAR [W/kg]	Exposure Condition	Position, Distance	Averaged Pmax [dBm]	Averaged Plimit [dBm]	RSI/DSI	Measured Pmax [dBm]	Measured Plimit [dBm]
16	Time-varying Tx power transmission	WLAN Band #1, Test Seq	2.4 GHz WLAN 802.11n 20 MHz	H	15.6	0.368	Body-Worn/Hotspot	Back Side, 5 mm	18	15	0	18.657	15.589
17		WLAN Band #2, Test Seq	5 GHz WLAN 802.11ac 20 MHz, UNII1	E	13.3	0.409	Body-Worn	Back Side, 5 mm	17	13	0	17.192	13.109
18	WLAN - DSI Change	WLAN Band	2.4 GHz WLAN 802.11ac 20 MHz	J	15.72	0.178	Body-Worn/Hotspot	Back Side, 5 mm	16	15	0	16.629	14.292
19	WLAN - Call Drop	WLAN Band	2.4 GHz WLAN 802.11ac 20 MHz	J	12.71	0.199	Head	Left Cheek, 0mm	16	12.5	1	16.629	12.082
20	WLAN - Band/Ant Change	WLAN Band	2.4 GHz WLAN 802.11ac 20 MHz	J	15.72	0.178	Body-Worn/Hotspot	Back Side, 5 mm	16	15	0	16.629	14.292
21	WLAN SAR Exposure Switch - DBS Test	WLAN Band #1	2.4 GHz WLAN 802.11ac 20 MHz	J	15.72	0.178	Body-Worn/Hotspot	Back Side, 5 mm	16	15	0	16.629	14.292
		WLAN Band #2	5 GHz WLAN 802.11ac 20 MHz, UNII3	E	13.3	0.409	Body-Worn	Back Side, 5 mm	18	13	0	17.192	13.109
		2.4 GHz WLAN + 5 GHz WLAN	2.4 GHz WLAN 802.11g/n 20 MHz	J	15.72	0.178	Body-Worn/Hotspot	Back Side, 5 mm	18	15	0	17.674	14.942
			5 GHz WLAN 802.11n 20 MHz, UNII3	E	13.3	0.409	Body-Worn	Back Side, 5 mm	18	13	0	17.742	12.116

Table 2-3
Part 2 Test Plan - C-TAS Test Case

Test Case	Test Scenario (Sub 6)	Tech	Band/Config	Antenna	Part 1 Measured Conducted Power [dBm]	Part 1 Measured SAR [W/kg]	Exposure Condition	Position, Distance	Averaged Pmax [dBm]	Averaged Plimit [dBm]	RSI/DSI	Measured Pmax [dBm]	Measured Plimit [dBm]
22	C-TAS	NR + WLAN + BT	NR n77	F	14.72	0.596	Body-Worn/Hotspot	Back Side, 5 mm	26.5	14	0	16.12	13.47
			5 GHz WLAN 802.11ac 20 MHz, UNII3	E	13.3	0.409	Body-Worn	Back Side, 5 mm	18	13	0	17.742	12.893
			Bluetooth	H	13.94	0.26	Body-Worn/Hotspot	Back Side, 5 mm	14	14	0	12.39	12.62

Part 1 Measured Conducted Powers were converted to frame average powers for the TDD modes.

2.2. TAS Test Cases and Notes:

1. Time-varying Tx power transmission: Test cases 1-8 listed in Table 2-1 and test cases 16-17 in Table 2-2 above are selected to test with test sequences.
2. Change in call: Test case 9 in Table 2-1 and test case 19 in Table 2-2 are selected for change in call or call drop test cases.
3. RSI/DSI Switch: Test case 10 in Table 2-1 and test case 18 in Table 2-2 are selected for RSI/DSI switch.
4. Reselection in a call: Test case 11 in Table 2-1 is selected to represent technology switching from LTE to NR.
5. Antenna/Band Switch: Test case 12 in Table 2-1 and test case 20 in Table 2-2 are selected for handover test from an antenna/band within one technology group to another antenna/band in the same RSI/DSI.
6. Interband ULCA: Test case 13 in Table 2-1 is selected for LTE Interband ULCA test case (LTE B12 + LTE B66, Ant A, RSI =0).
7. ENDC SAR Exposure Switching: Test case 14 is selected for SAR exposure switching test in one of the supported simultaneous WWAN transmission scenario (LTE B12 + Sub6 NR n66).
8. ENDC NSA Antenna Switching: Test case 15 is selected for ENDC NR handover test from one NR antenna (NR n66, Ant A, RSI=0) to another NR antenna in the different antenna group (NR n77, Ant F, RSI=0) while LTE remains connected on the same antenna (LTE B12, Ant A, RSI = 0).
9. Dual Band Simultaneous (DBS): Test Case 21 in Table 2-2 is selected for dual band simultaneous transmission test case for 2.4GHz WLAN and 5GHz WLAN.
10. C-TAS (WWAN – WLAN – BT) : Test Case 22 in Table 2-3 is selected for C-TAS test case with NR n77 + 5 GHz WLAN + BT technologies.
11. All switching, EN-DC, and C-TAS compliance continuity test cases are selected to be performed within the same antenna group.
12. LTE Intra-band ULCA, FR1 Inter-band ULCA and FR1 UL MIMO are not supported within the same antenna groups by the DUT.

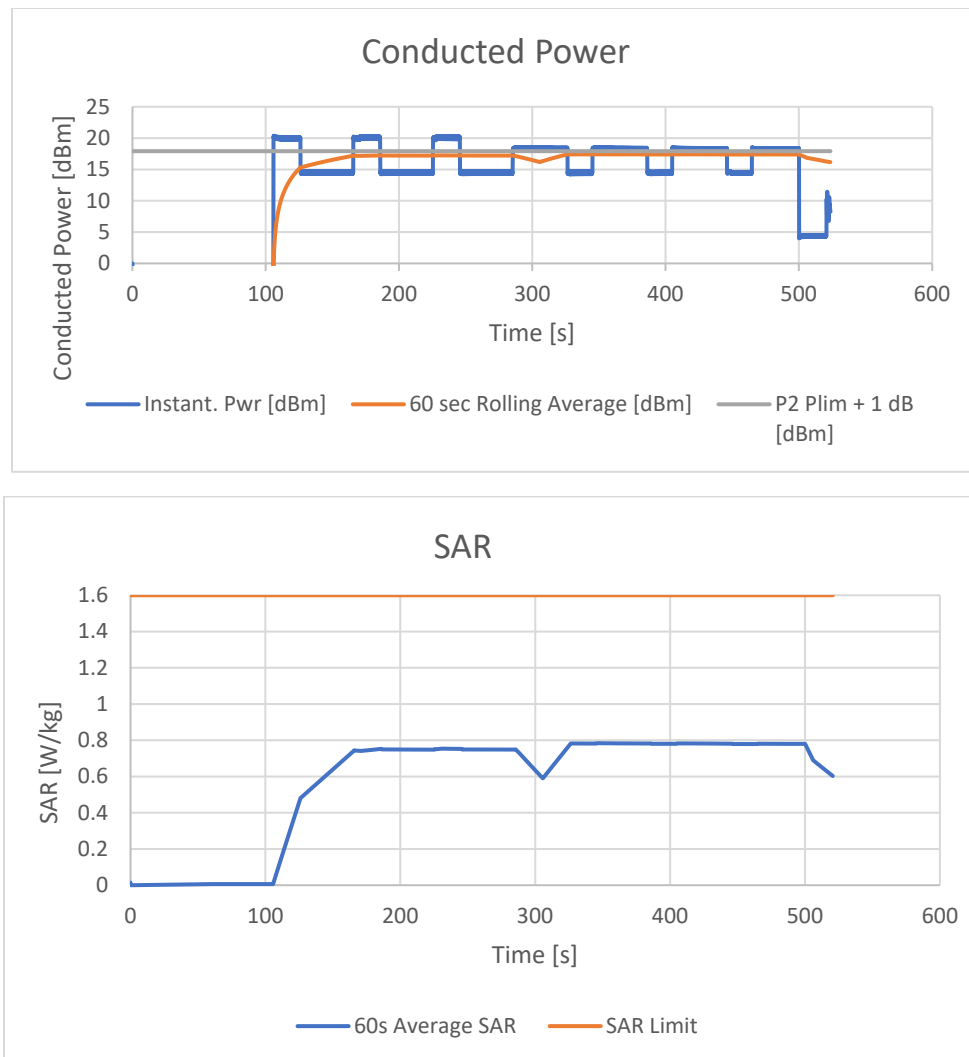
3. Part 2 S.LSI Test Results

3.1. Conducted Tx Cases (Freq < 6 GHz)

Time-averaged conducted tx power is converted into time-averaged 1g SAR in the figures below. Please see below for time-averaged 1g SAR and SAR limit that the test result complies. Section 3 contains detailed information regarding the test configurations.

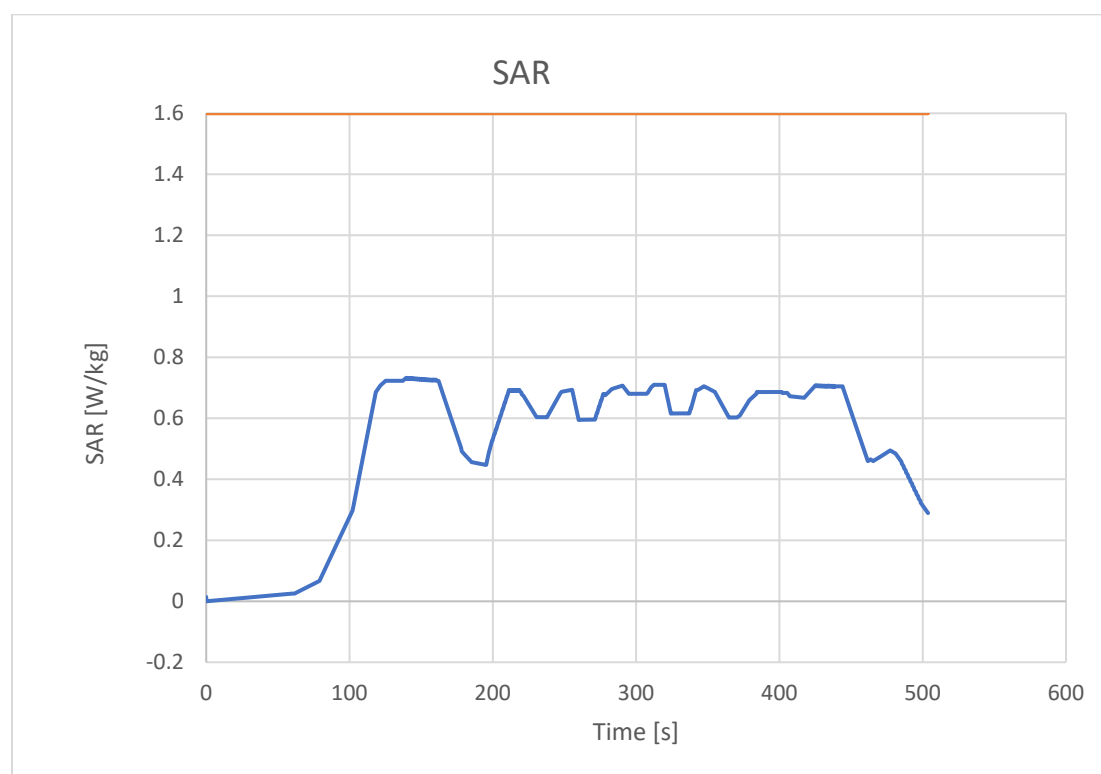
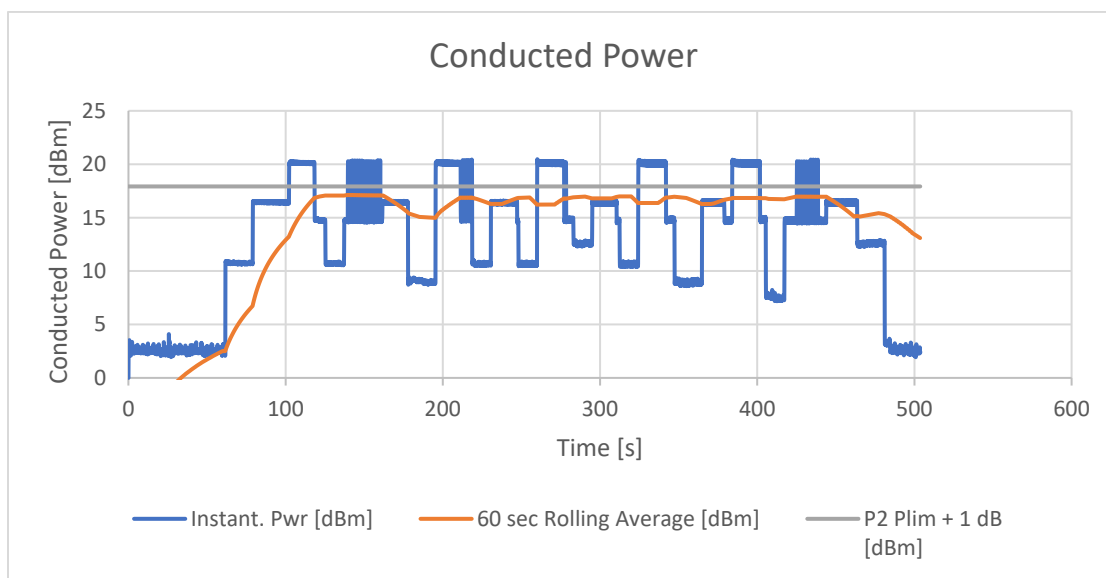
3.1.1. GPRS 1900

Test Sequence A



	W/kg
FCC SAR Limit	1.6
Max 60 sec time-averaged 1g SAR	0.784
Validated: Max time-averaged SAR is within device uncertainty of measured SAR at Plimit	

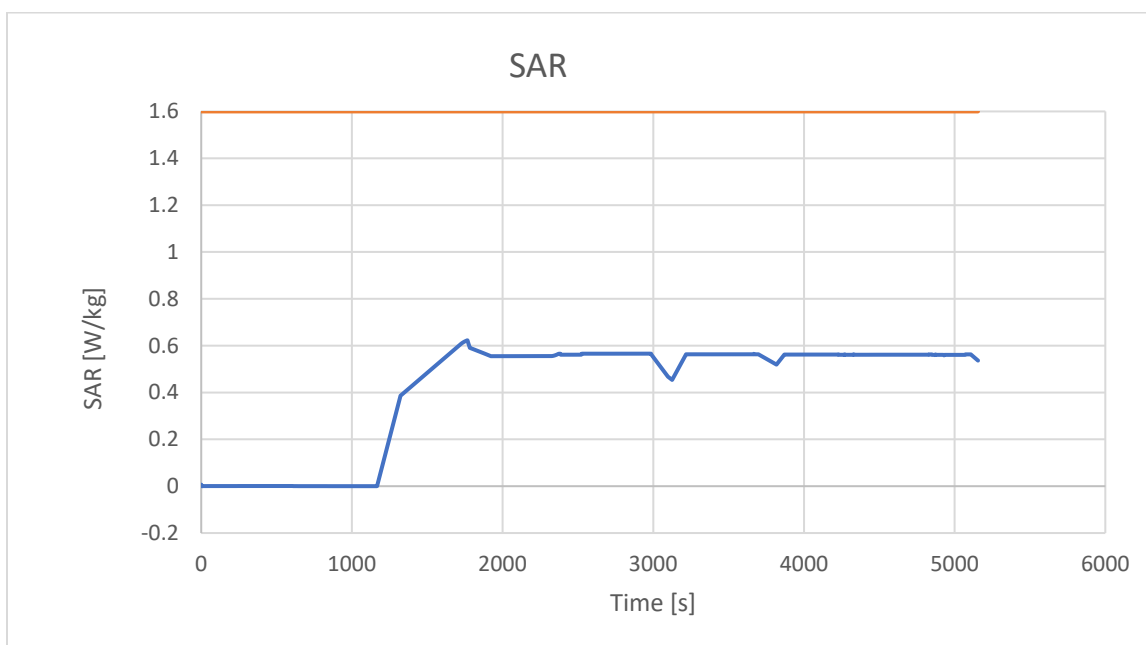
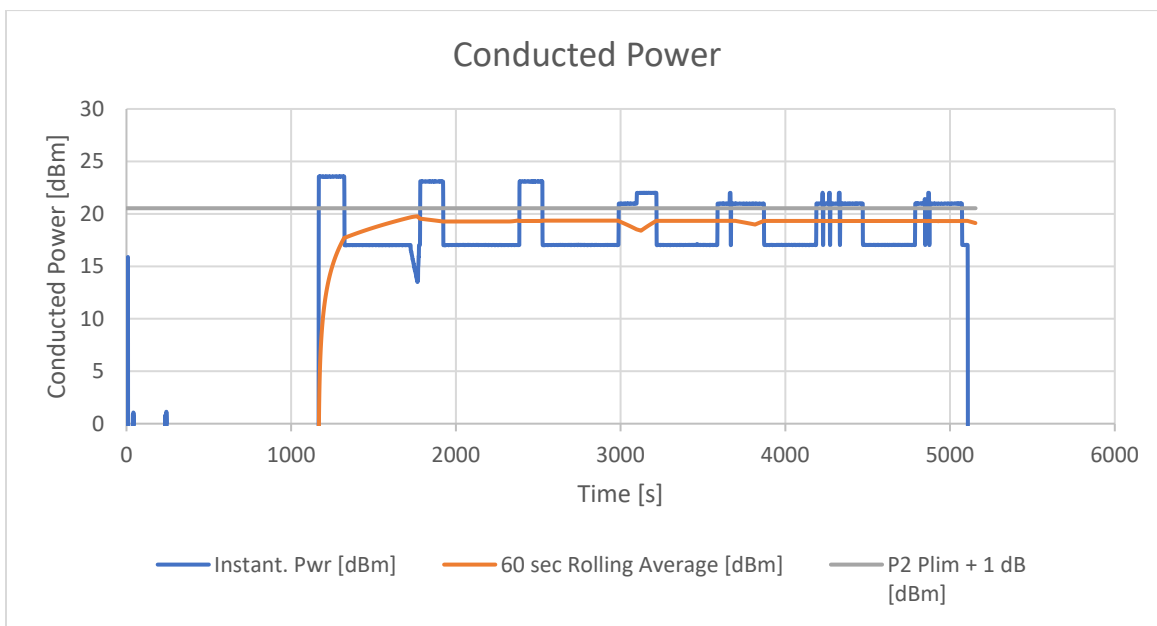
Test Sequence B



	W/kg
FCC SAR Limit	1.6
Max 60 sec time-averaged 1g SAR	0.733
Validated: Max time-averaged SAR is within device uncertainty of measured SAR at Plimit	

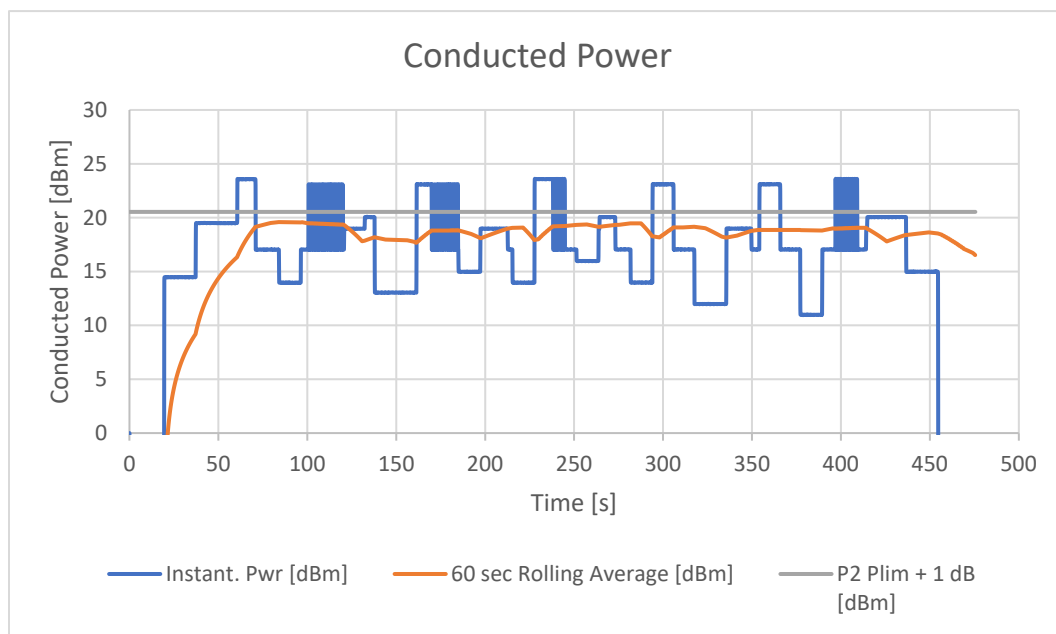
3.1.2. UMTS B5

Test Sequence A



	W/kg
FCC SAR Limit	1.6
Max 60 sec time-averaged 1g SAR	0.623
Validated: Max time-averaged SAR is within device uncertainty of measured SAR at Plimit	

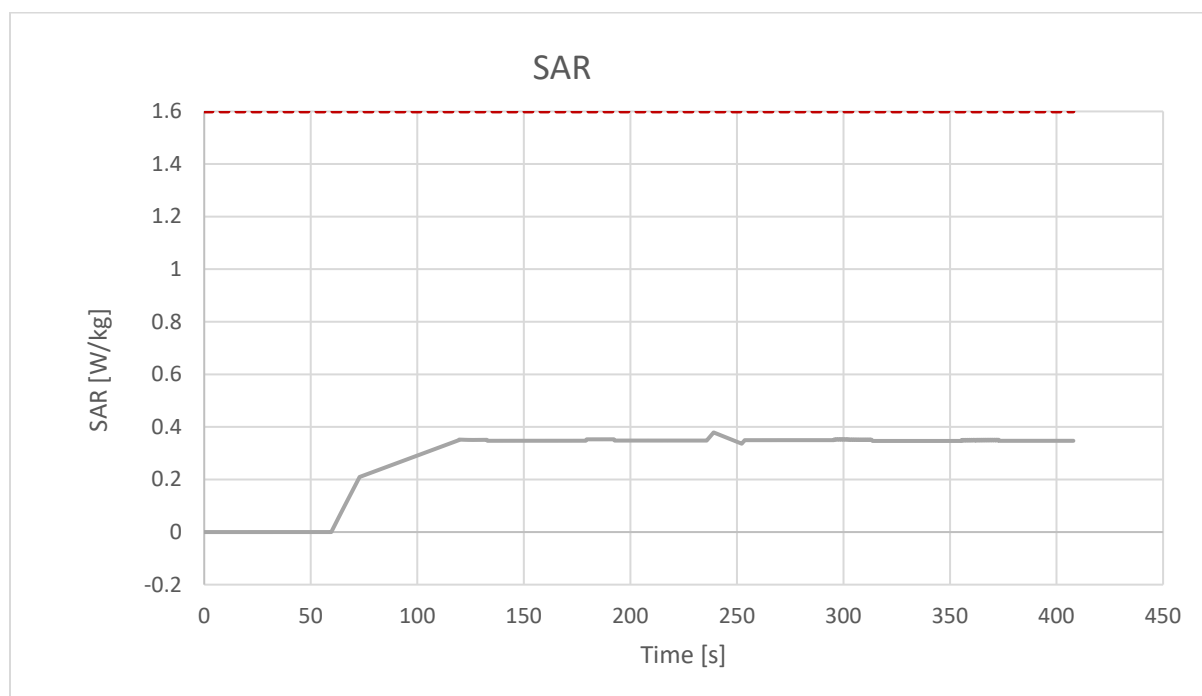
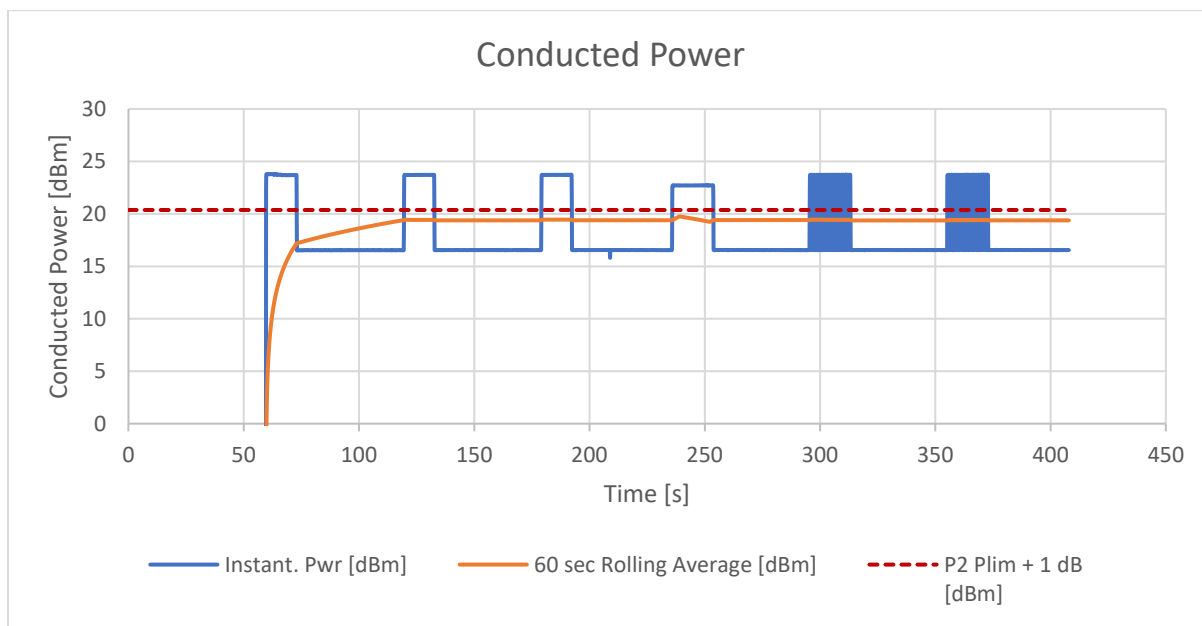
Test Sequence B



	W/kg
FCC SAR Limit	1.6
Max 60 sec time-averaged 1g SAR	0.597
Validated: Max time-averaged SAR is within device uncertainty of measured SAR at Plimit	

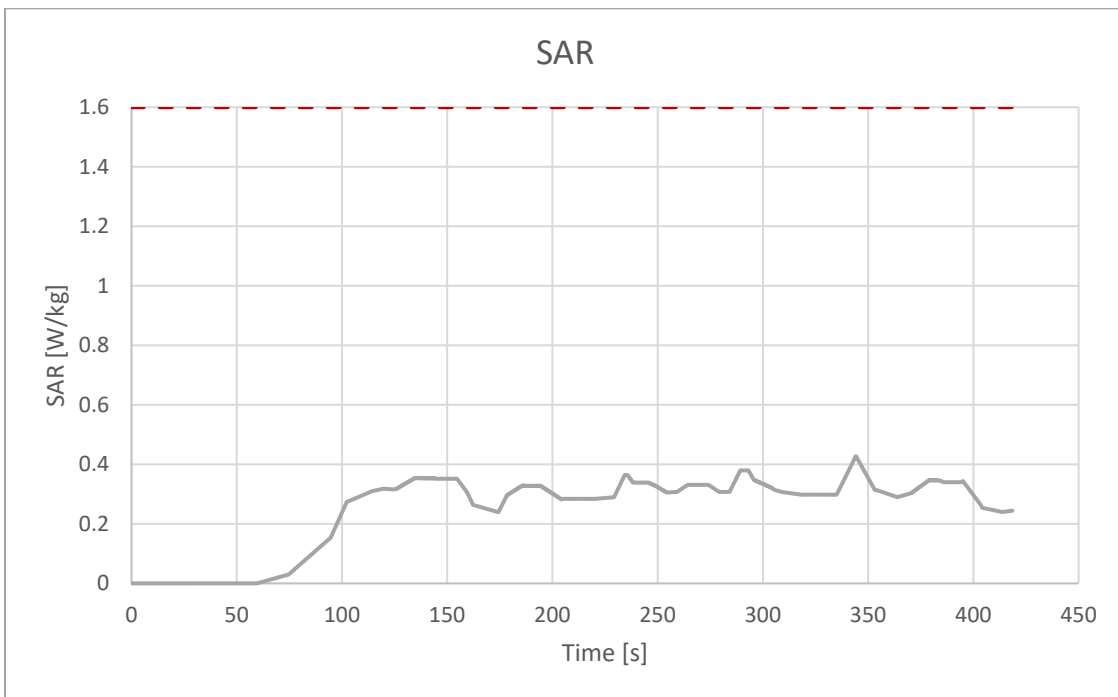
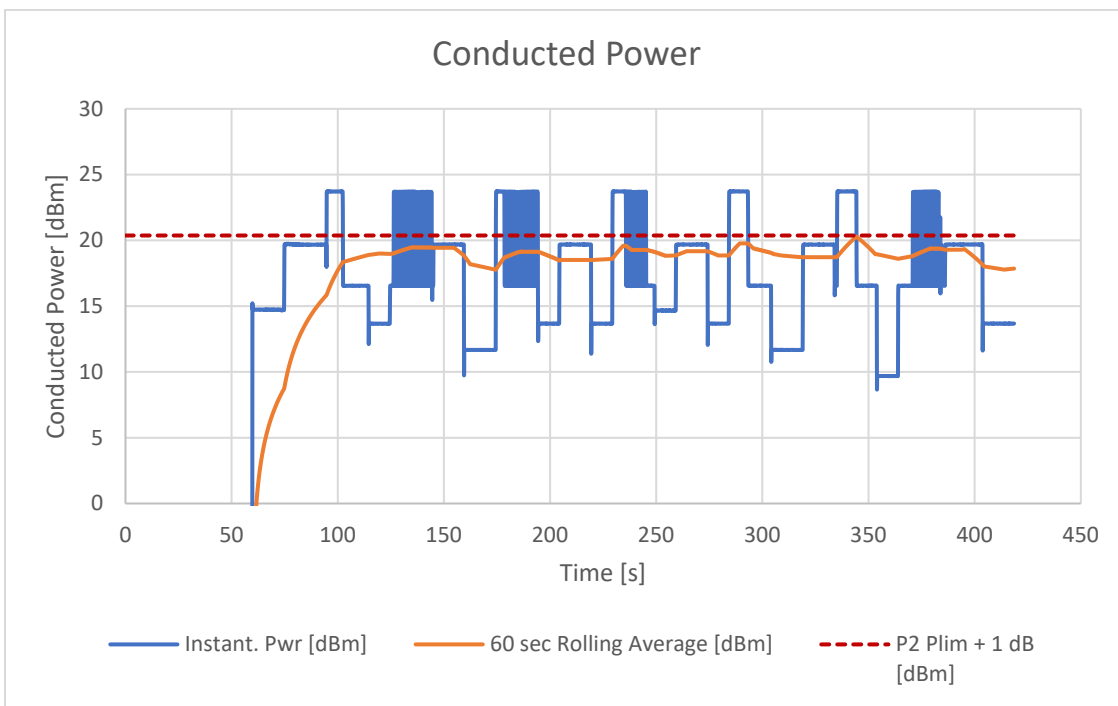
3.1.3. LTE B13

Test Sequence A



	W/kg
FCC SAR Limit	1.6
Max 60 sec time-averaged 1g SAR	0.379
Validated: Max time-averaged SAR is within device uncertainty of measured SAR at Plimit	

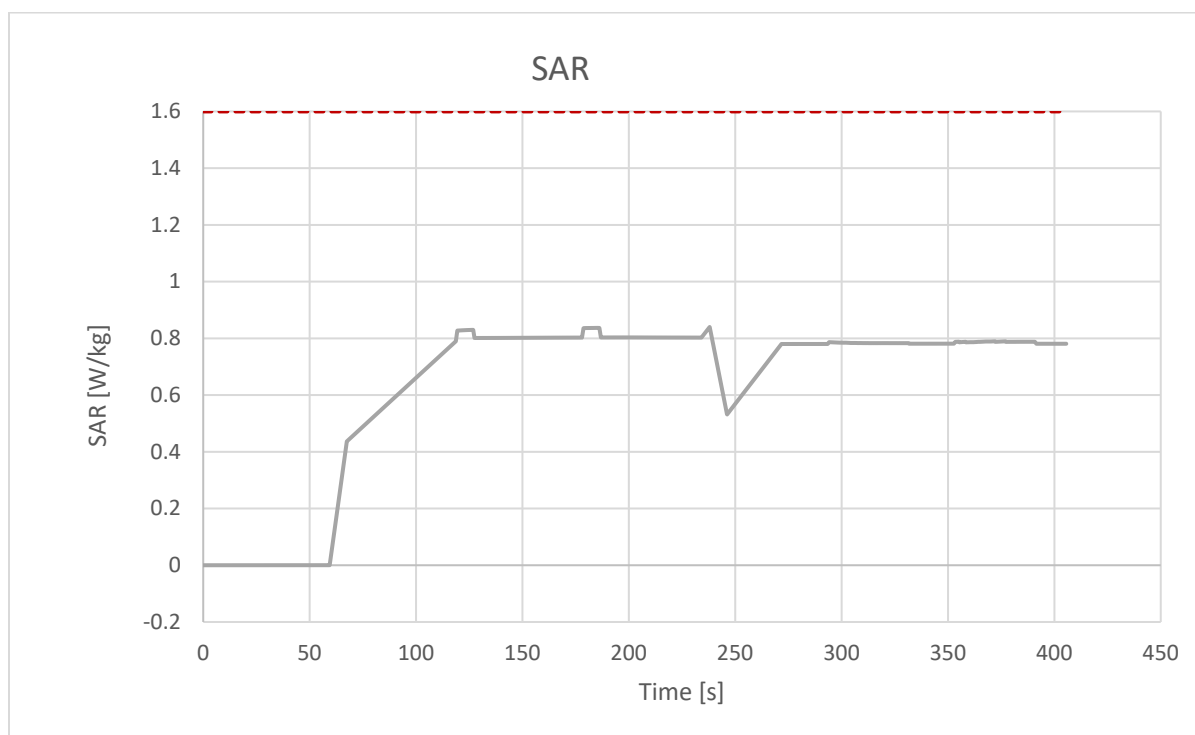
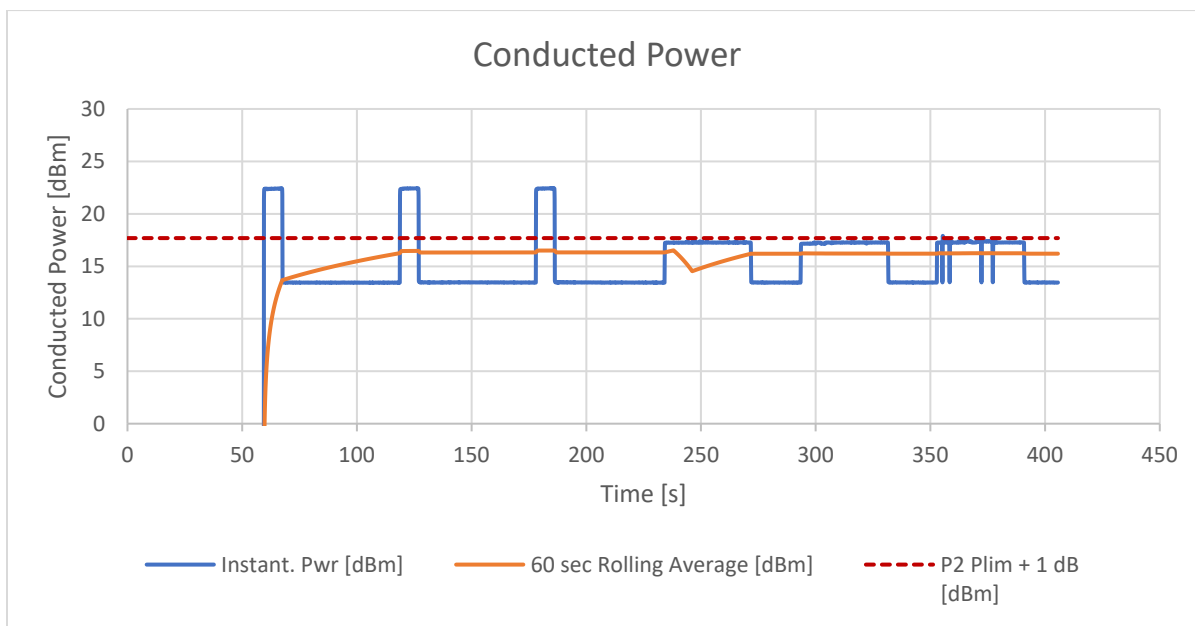
Test Sequence B



	W/kg
FCC SAR Limit	1.6
Max 60 sec time-averaged 1g SAR	0.428
Validated: Max time-averaged SAR is within device uncertainty of measured SAR at Plimit	

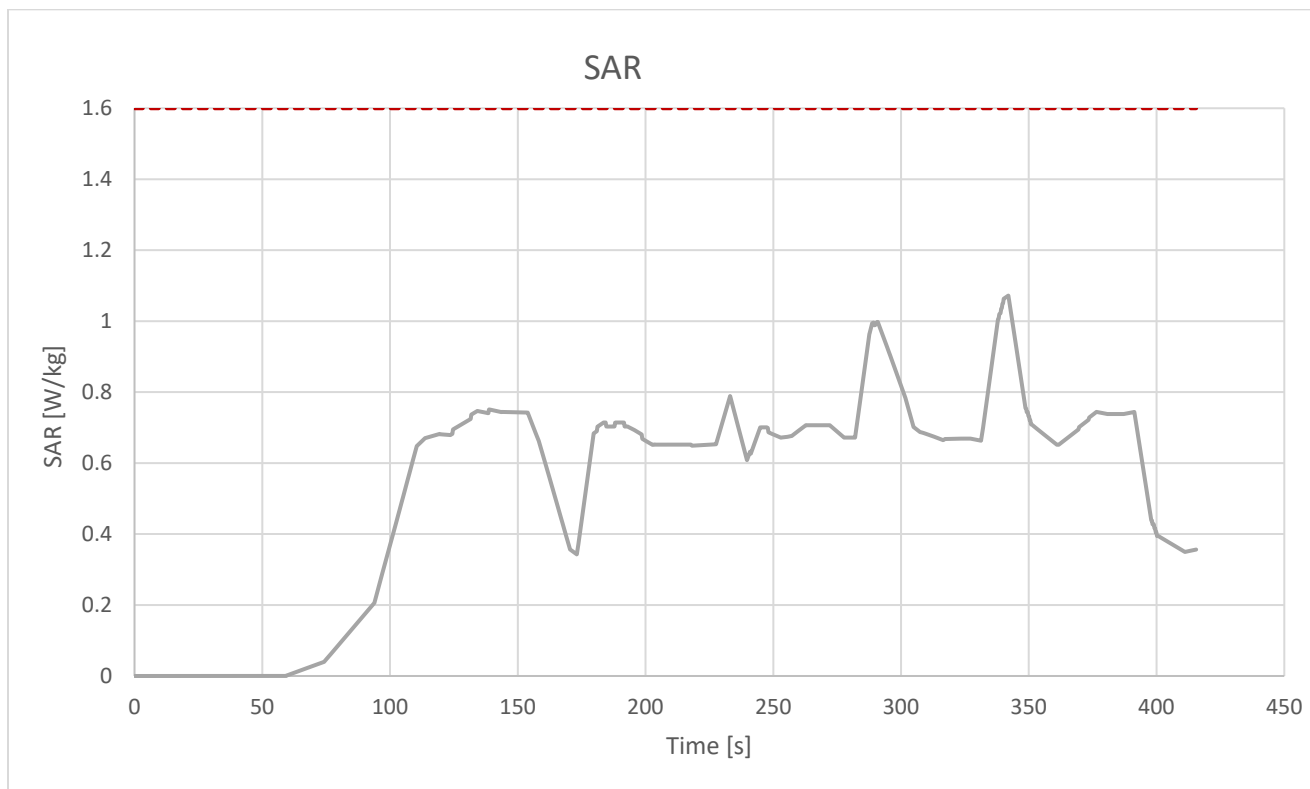
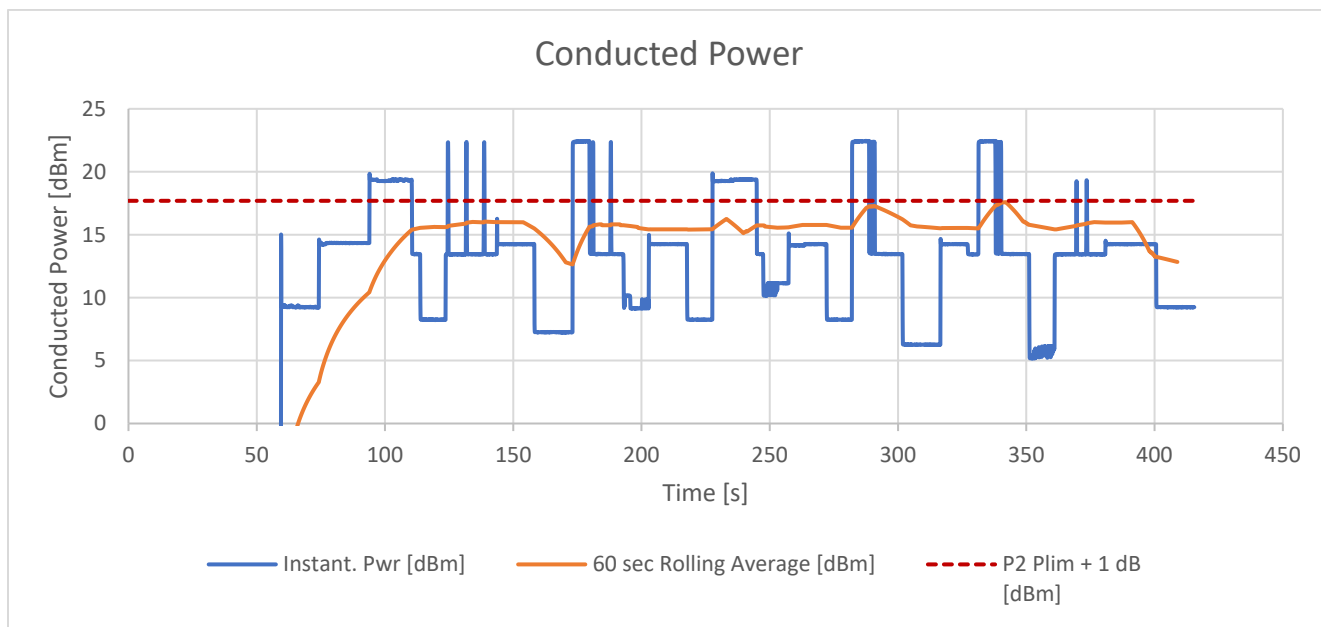
3.1.4. Sub6 NR n66

Test Sequence A



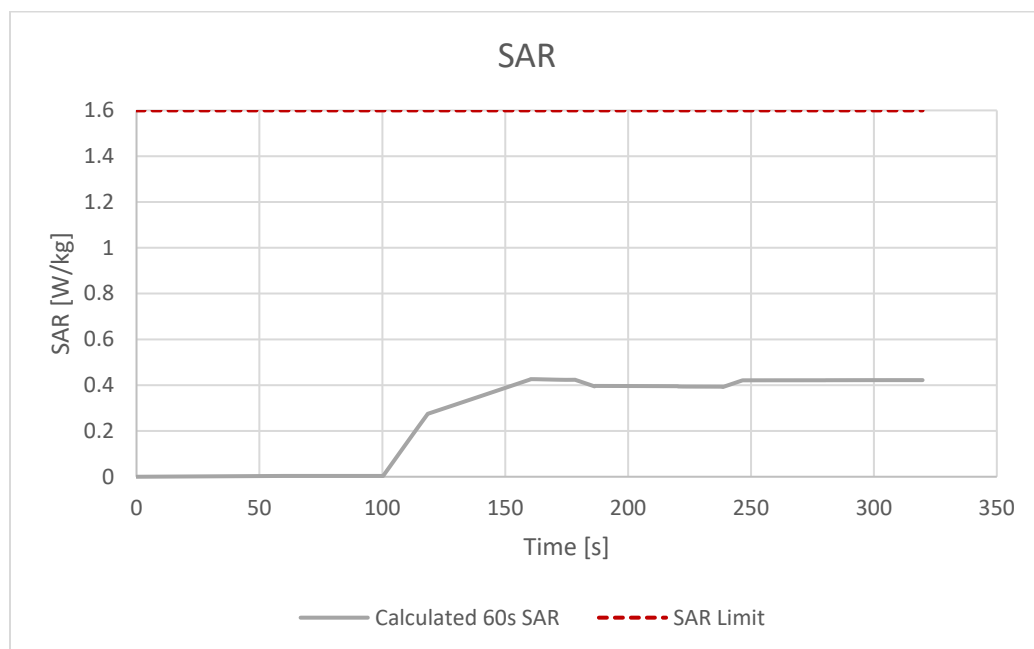
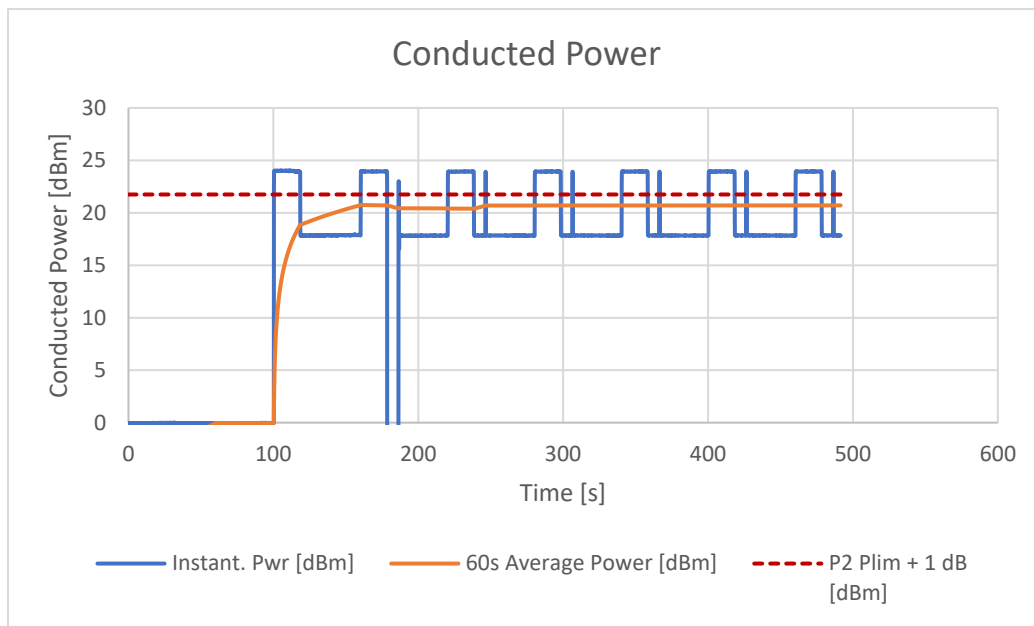
	W/kg
FCC SAR Limit	1.6
Max 60 sec time-averaged 1g SAR	0.840
Validated: Max time-averaged SAR is within device uncertainty of measured SAR at Plimit	

Test Sequence B



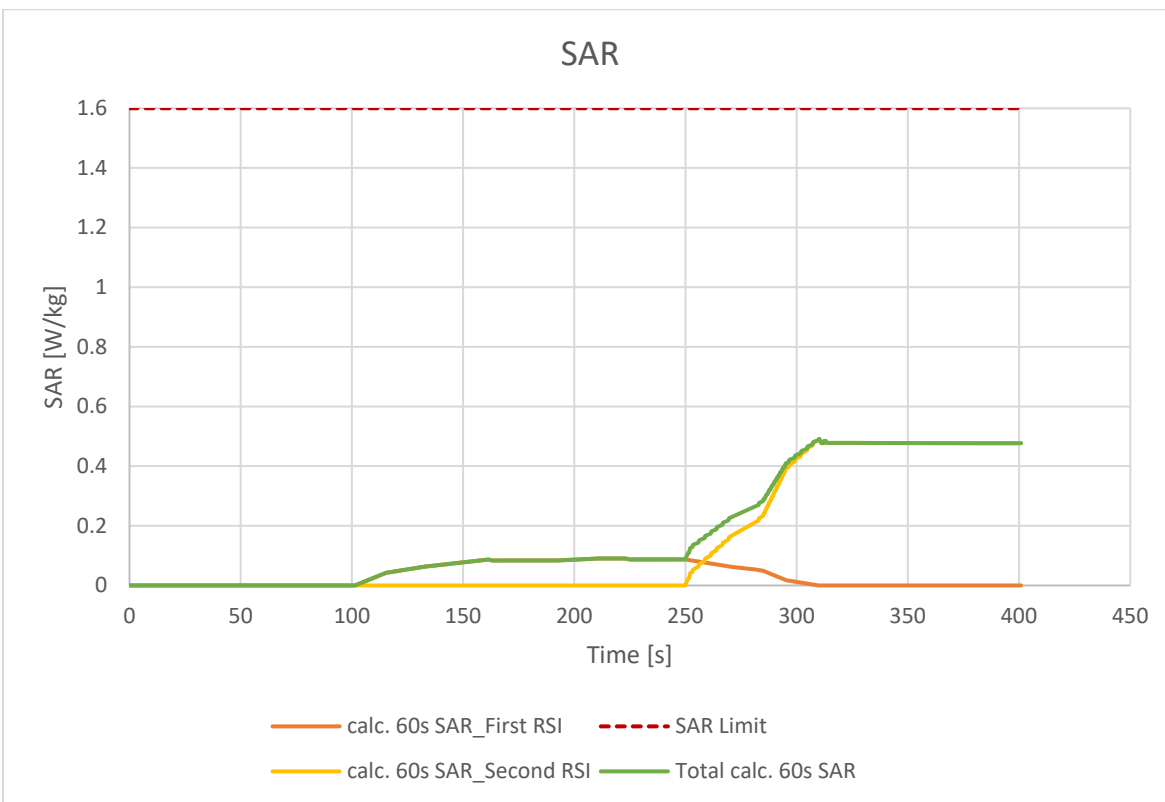
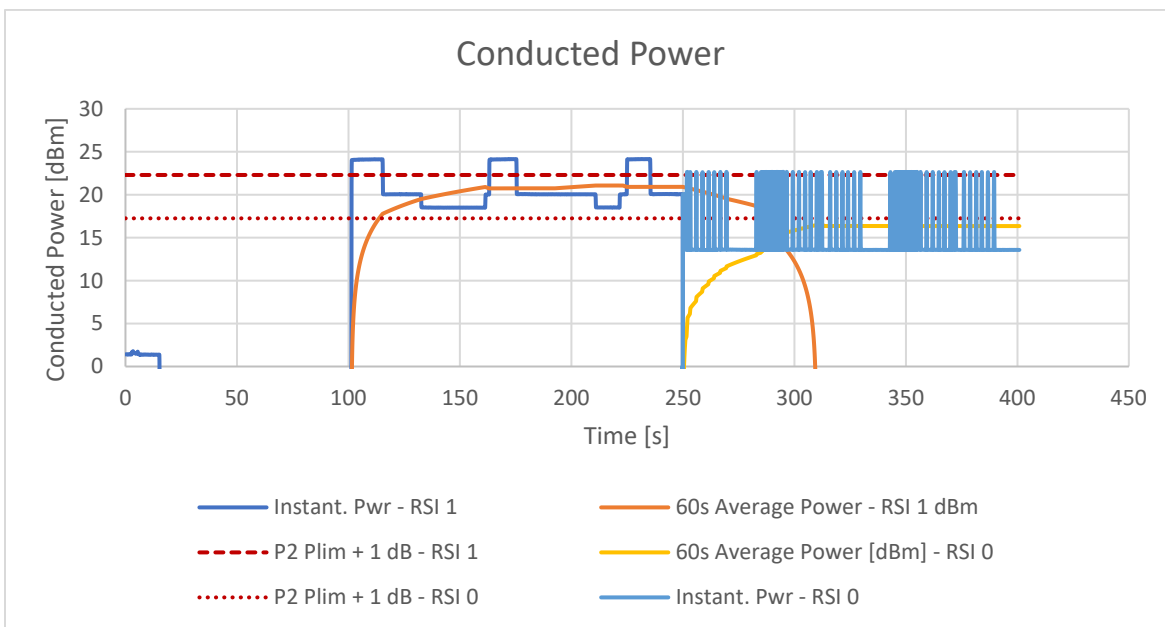
	W/kg
FCC SAR Limit	1.6
Max 60 sec time-averaged 1g SAR	1.072
Validated: Max time-averaged SAR is within device uncertainty of measured SAR at Plimit	

3.1.5. Call Drop – LTE B13



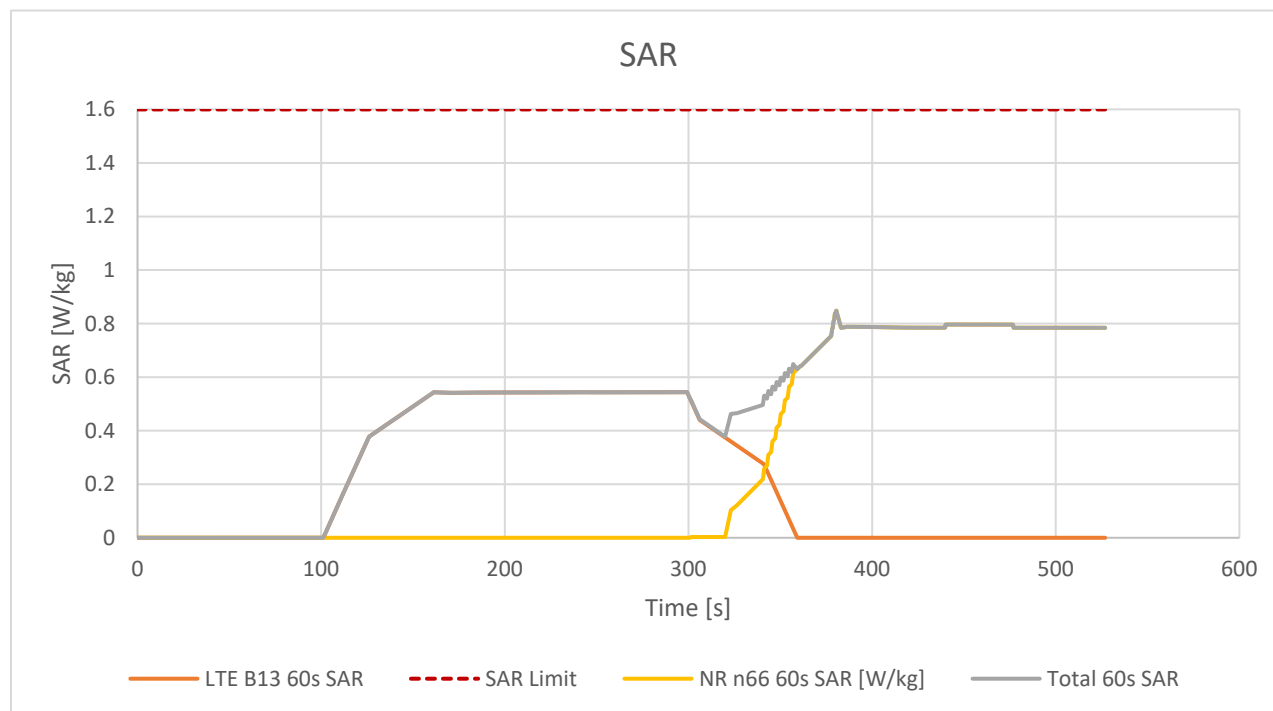
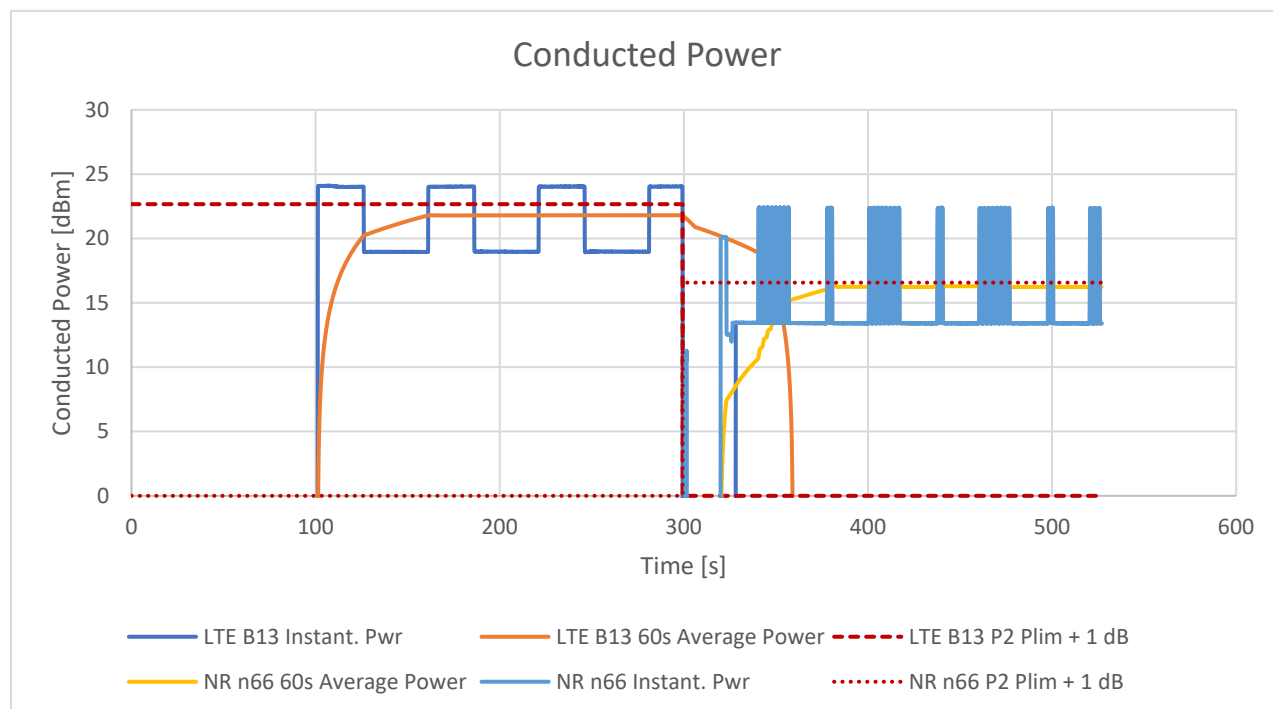
	W/kg
FCC SAR Limit	1.6
Max 60 sec time-averaged 1g SAR	0.426
Validated: Max time-averaged SAR is within device uncertainty of measured SAR at Plimit	

3.1.6. RSI Switch – UMTS B2



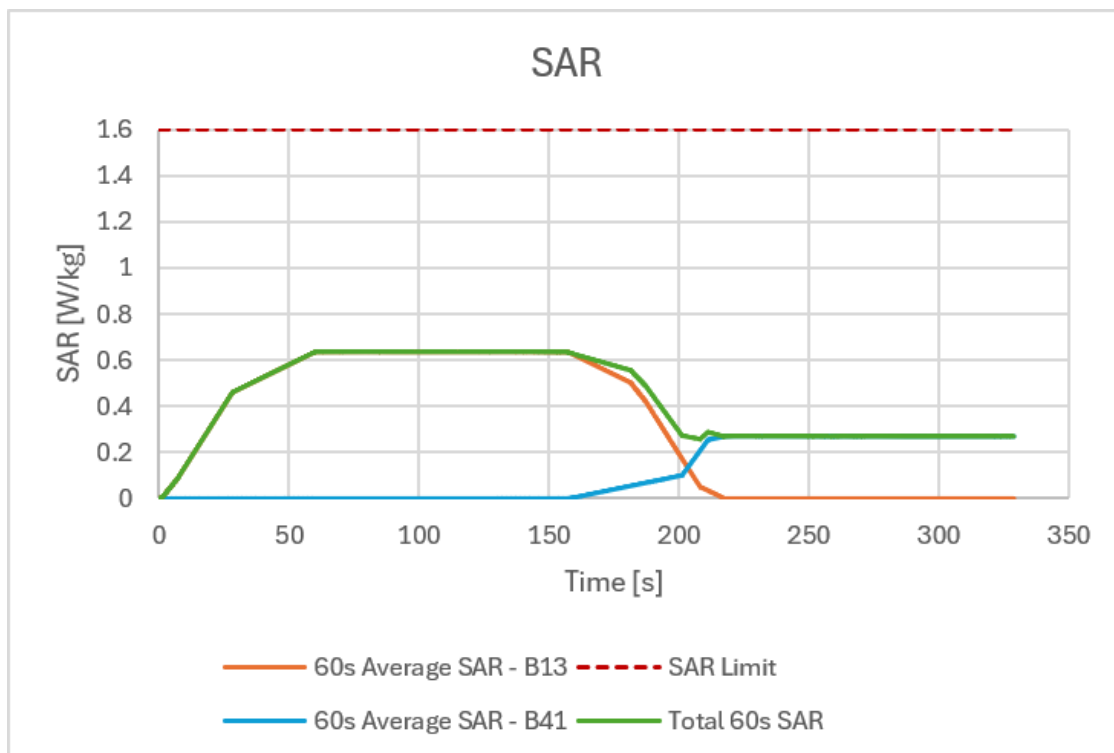
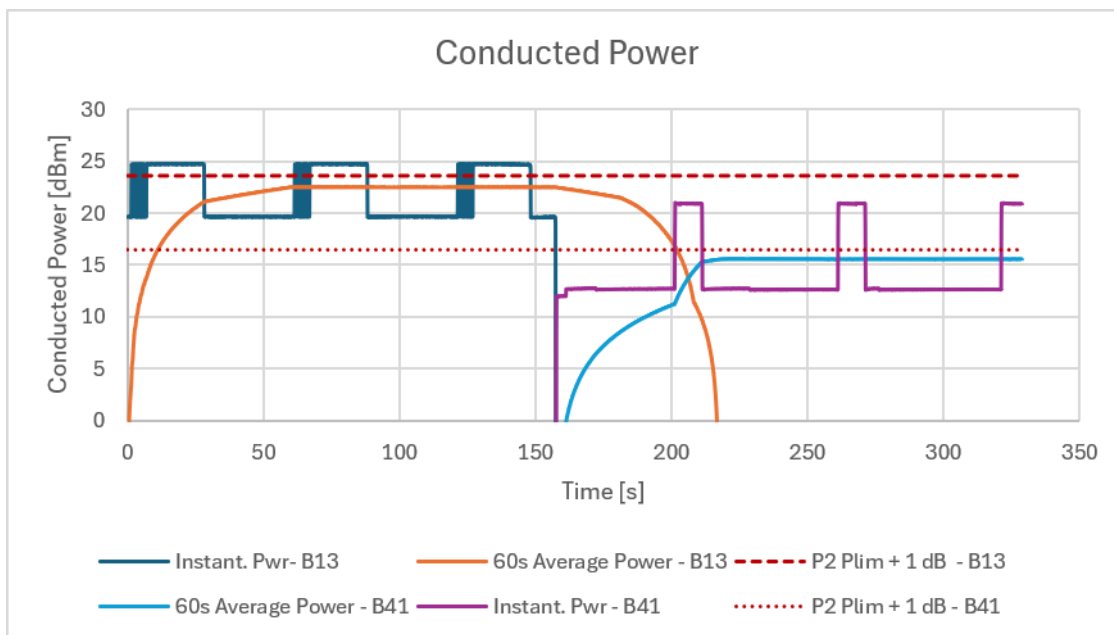
	W/kg
FCC SAR Limit	1.6
Max 60 sec time-averaged SAR	0.492
Validated: Max time-averaged SAR is within device uncertainty of measured SAR at Plimit	

3.1.7. Tech/Band Switch – LTE B13 to NR n66



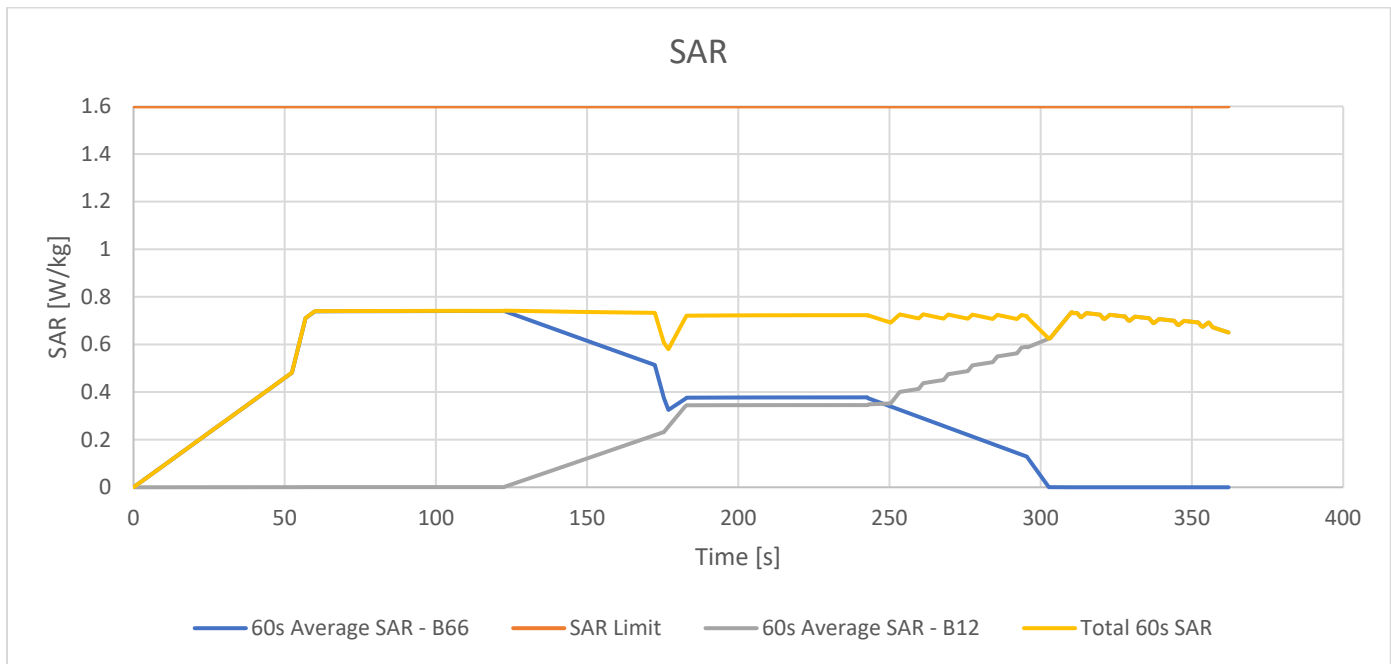
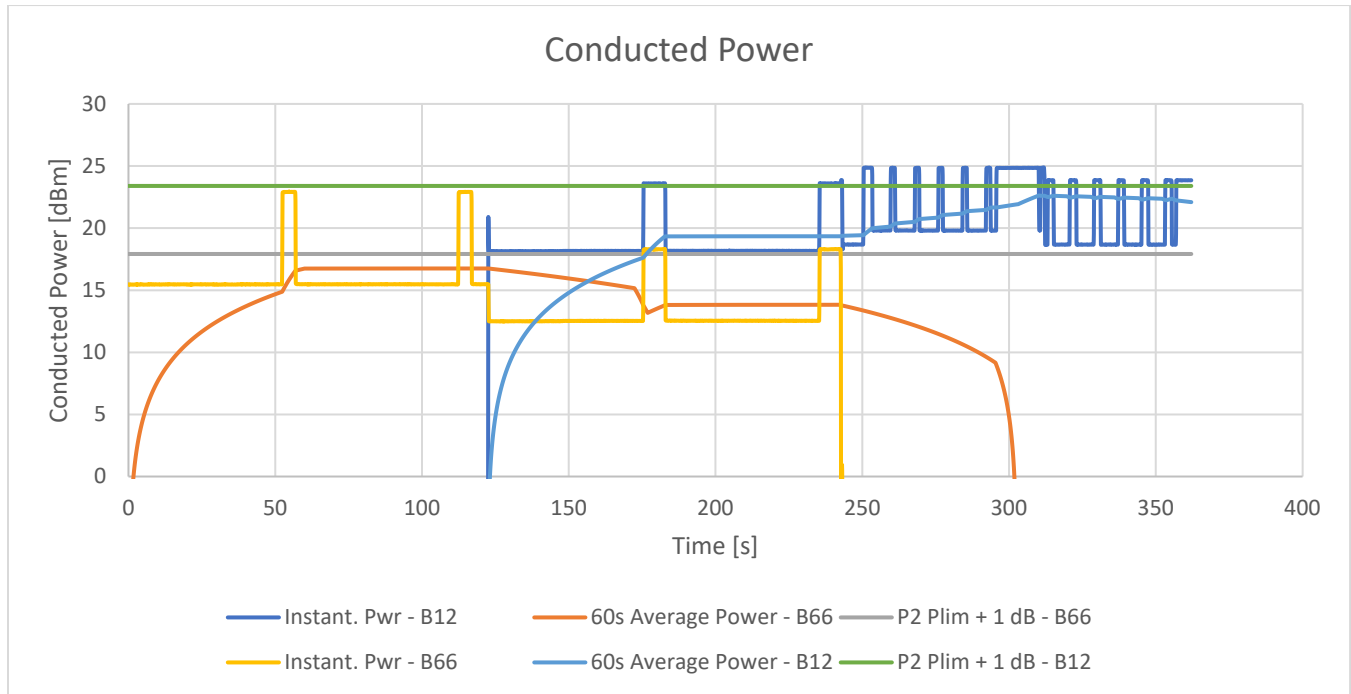
	W/kg
FCC SAR Limit	1.6
Max 60 sec time-averaged SAR	0.848
Validated: Max time-averaged SAR is within device uncertainty of measured SAR at Plimit	

3.1.8. Band/Antenna Switch – LTE B13 to LTE B41



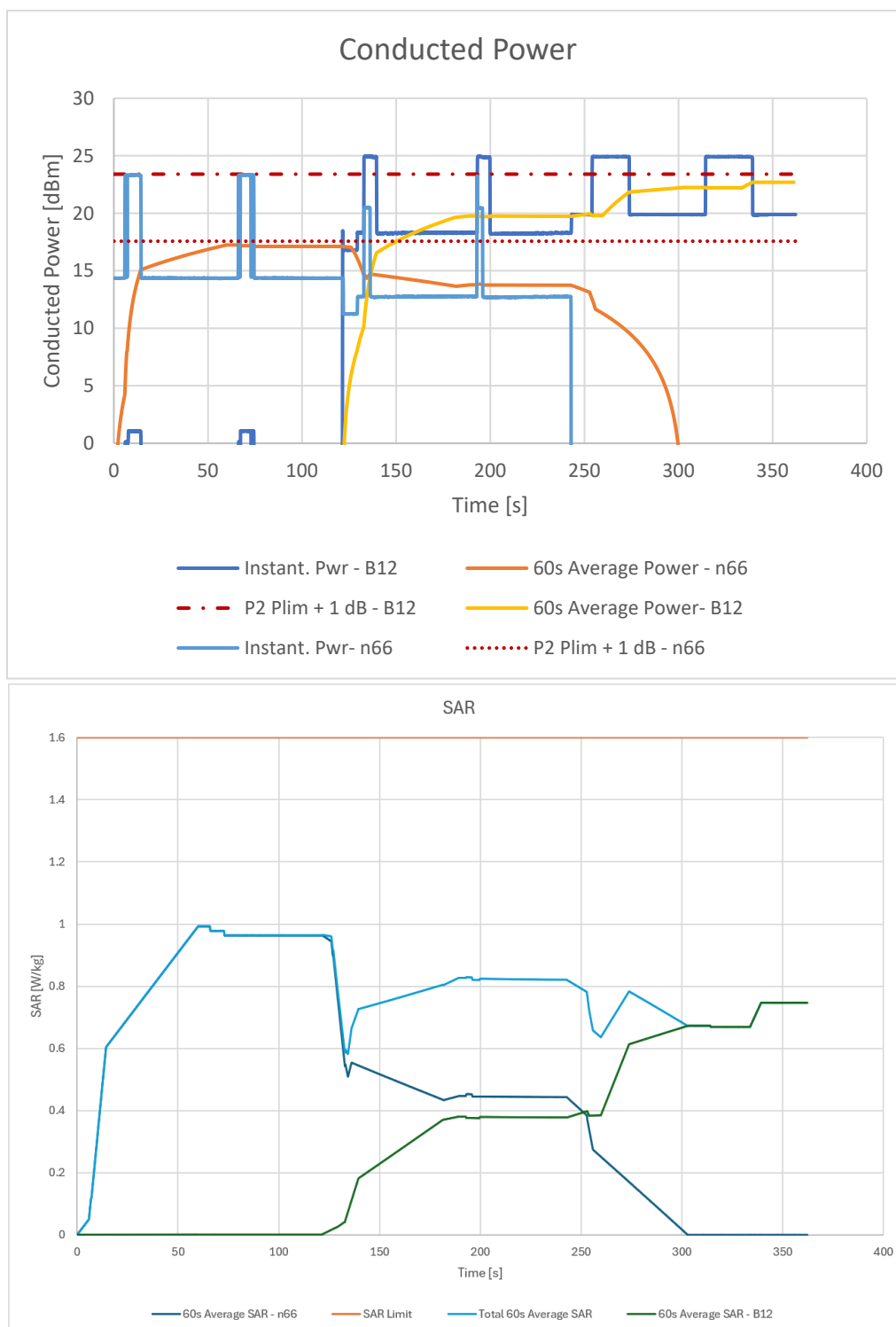
	W/kg
FCC SAR Limit	1.6
Max 60 sec time-averaged SAR	0.636
Validated: Max time-averaged SAR is within device uncertainty of measured SAR at Plimit	

3.1.9. LTE Interband ULCA



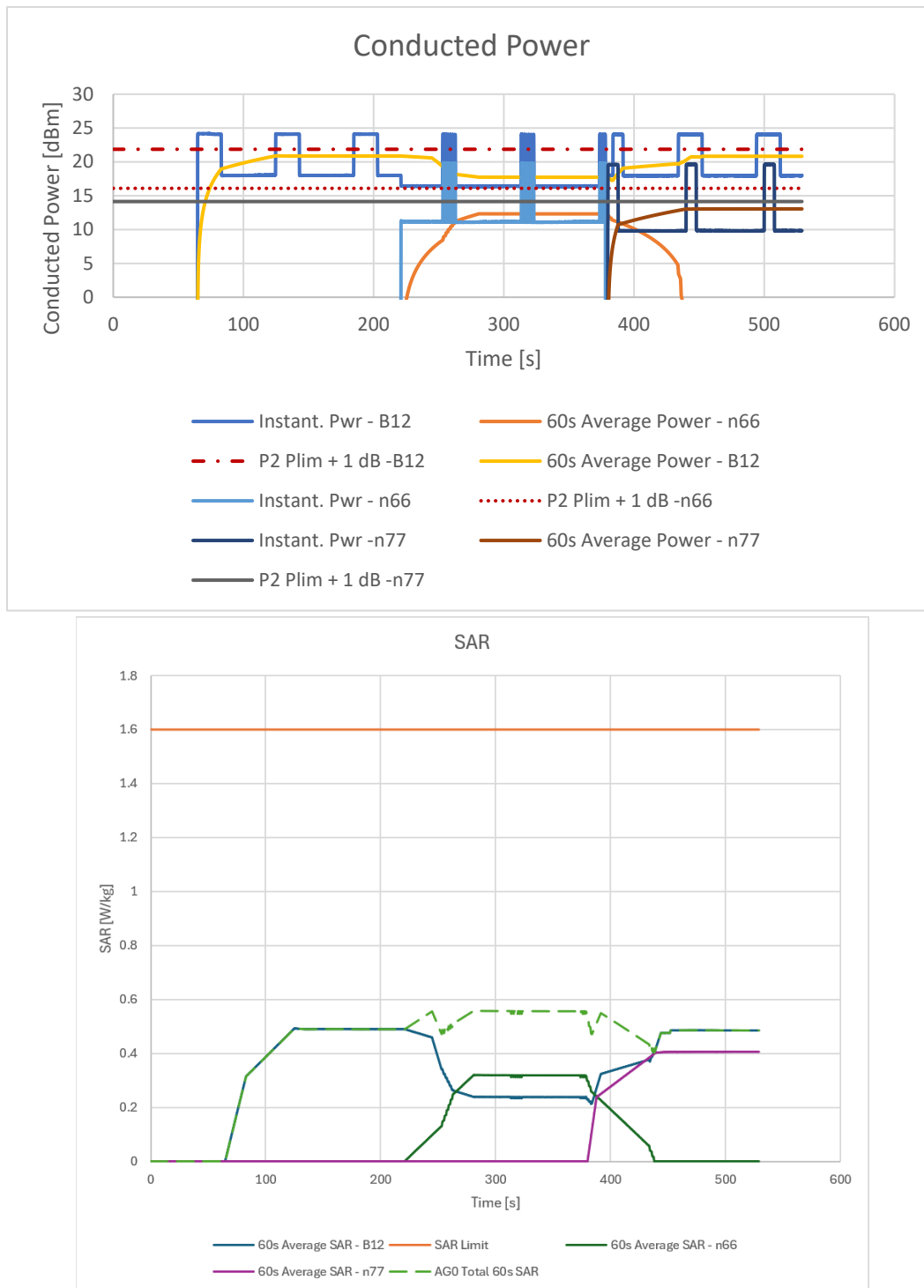
	W/kg
FCC SAR Limit	1.6
Max 60 sec time-averaged SAR	0.742
Validated: Max time-averaged SAR is within device uncertainty of measured SAR at Plimit	

3.1.10. SAR Exposure Switch – ENDC



	W/kg
FCC SAR Limit	1.6
Max time-averaged 60 sec SAR	0.993
Validated: Max time-averaged SAR is within device uncertainty of measured SAR at Plimit	

3.1.11. SAR Exposure Switch - ENDC (NR Antenna Switching)



	W/kg
FCC SAR Limit	1.6
Max time-averaged 60 sec SAR	0.558
Validated: Max time-averaged SAR is within device uncertainty of measured SAR at Plimit	

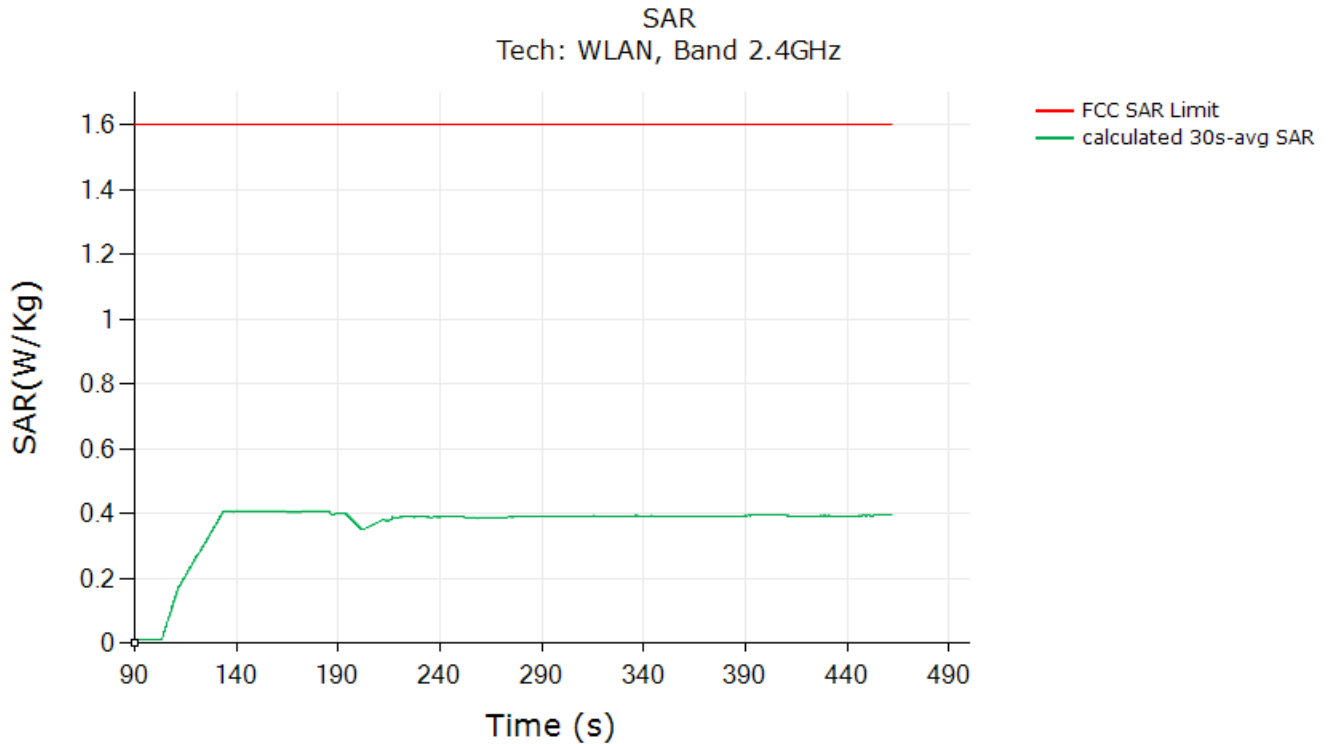
4. Qualcomm FastConnect Part 2 Test Results

4.1. Conducted Tx Cases (Freq < 6 GHz)

Time-averaged conducted Tx power is converted into time-averaged 1g SAR in the figures below. Please see below for time-averaged 1g SAR and SAR limit that the test result complies. Section 2 contains detailed information regarding the test configurations.

4.1.1. 2.4 GHz WLAN 802.11n

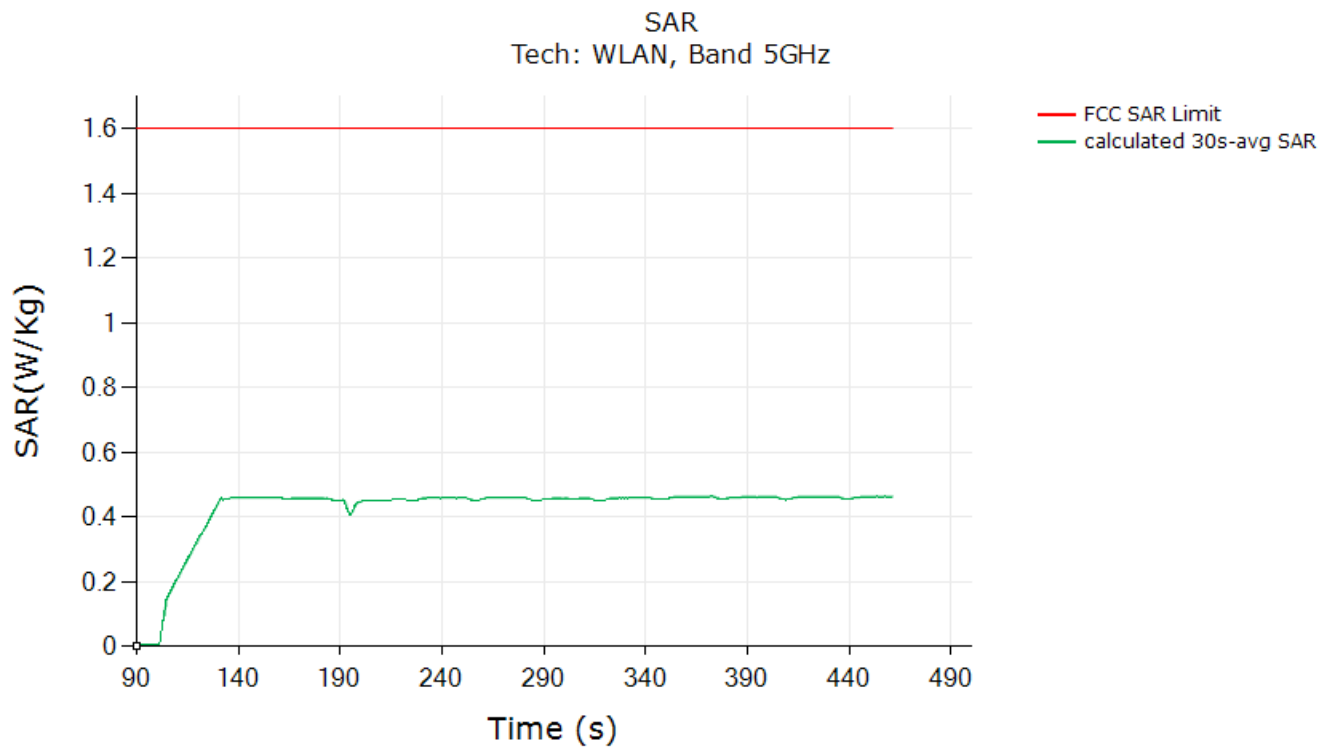
Test Sequence A



	W/kg
FCC SAR Limit	1.6
Max 30 sec time-averaged 1g SAR	0.408
Validated: Max time-averaged SAR is within device uncertainty of measured SAR at Plimit	

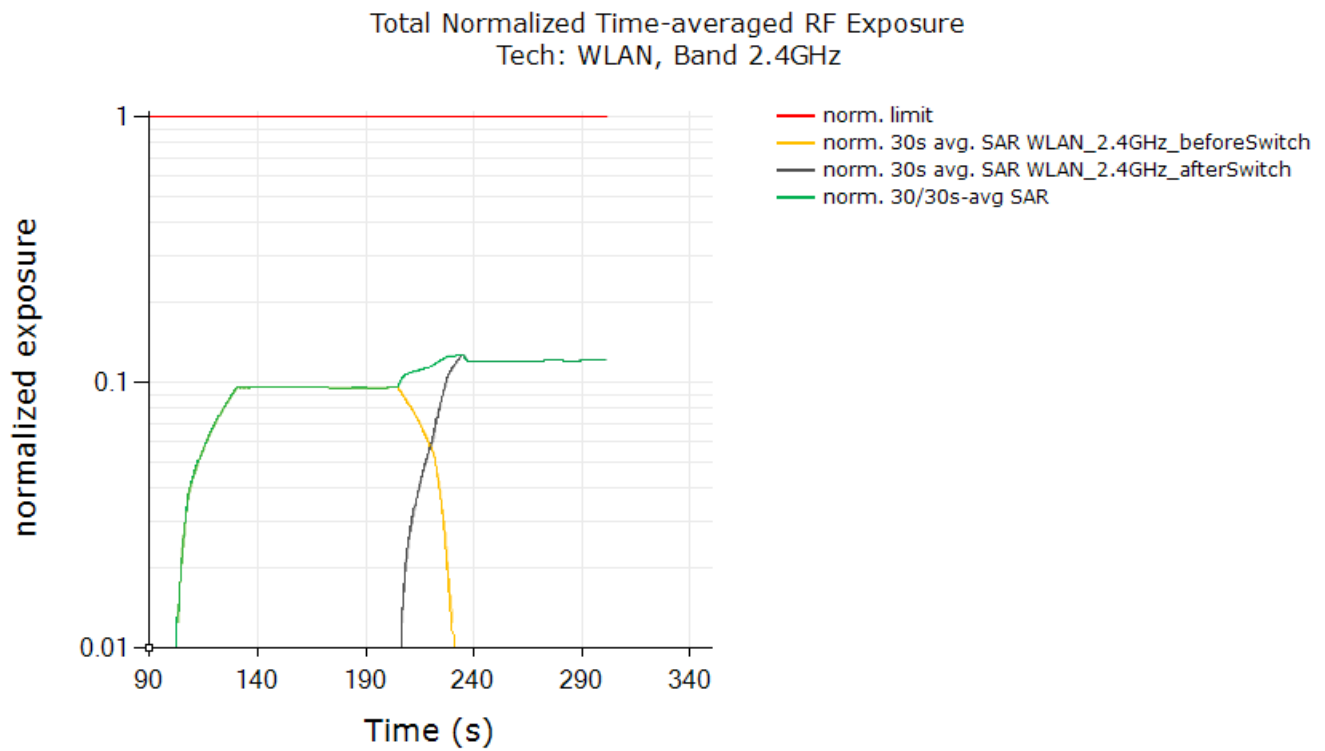
4.1.2. 5 GHz WLAN 802.11ac

Test Sequence A



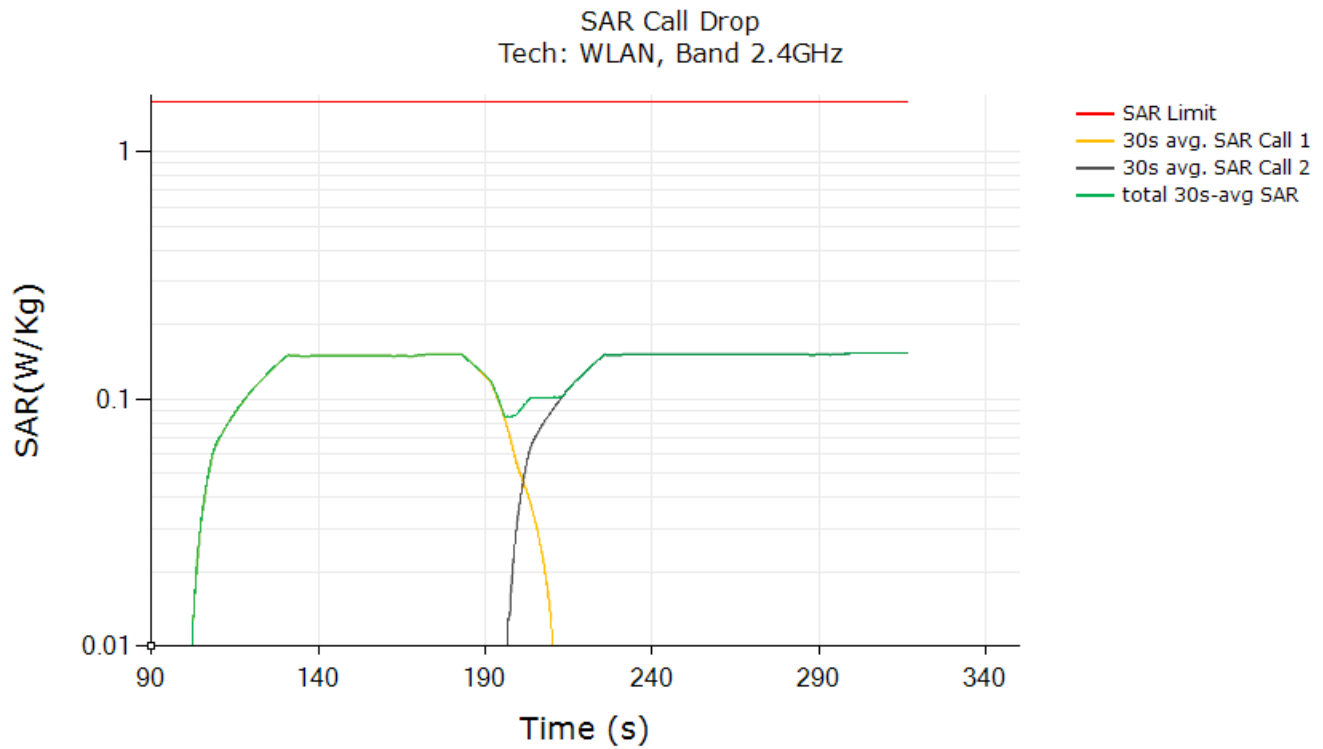
	W/kg
FCC SAR Limit	1.6
Max 30 sec time-averaged 1g SAR	0.464
Validated: Max time-averaged SAR is within device uncertainty of measured SAR at Plimit	

4.1.3. WLAN DSI Change



Normalized SAR Limit	1.0
Max time-averaged Normalized SAR	0.128
Validated: Max time-averaged SAR is within device uncertainty of measured SAR at Plimit	

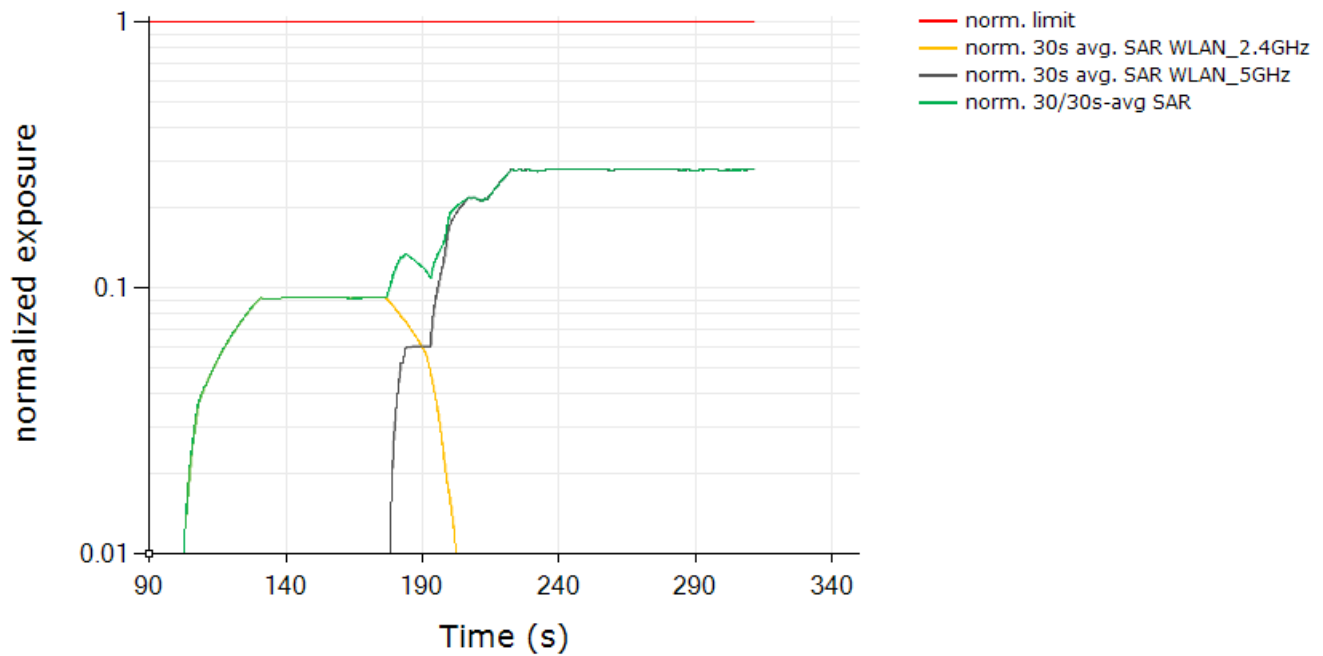
4.1.4. WLAN Call Drop Change



	W/kg
FCC SAR Limit	1.6
Max 30 sec time-averaged 1g SAR	0.153
Validated: Max time-averaged SAR is within device uncertainty of measured SAR at Plimit	

4.1.5. WLAN Band/Antenna Change

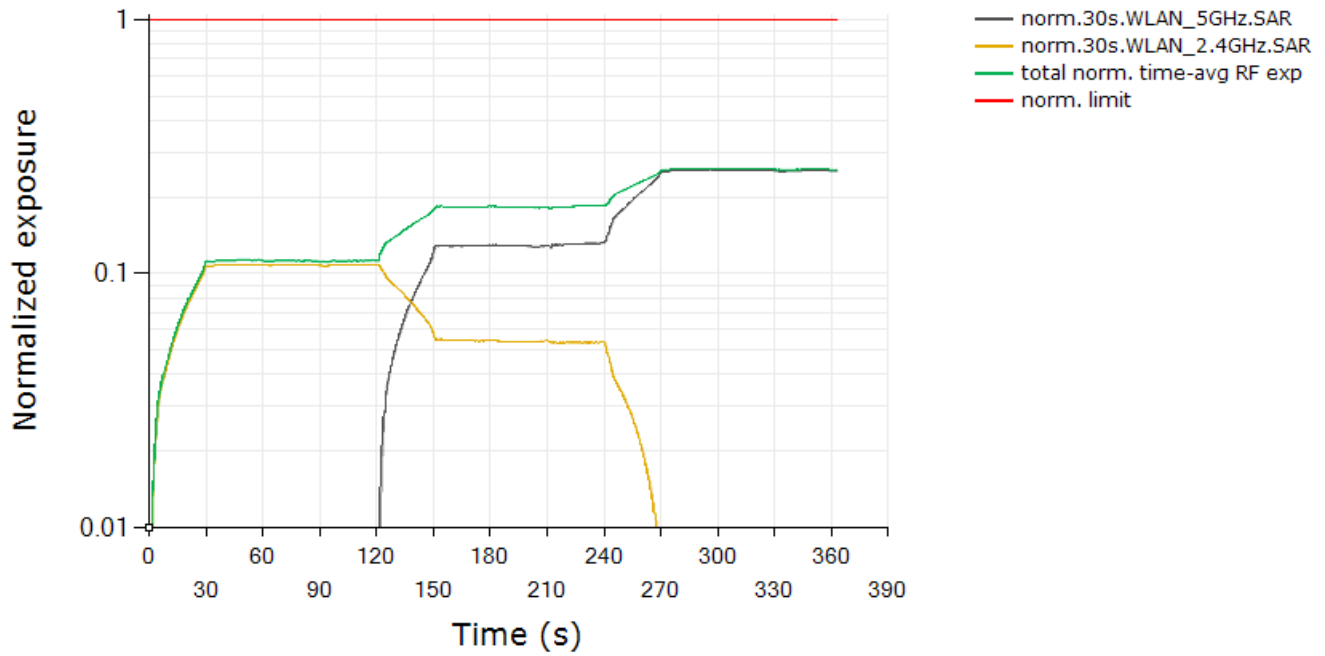
Total Normalized Time-averaged RF Exposure
Tech: WLAN, Band 2.4GHz / Tech: WLAN, Band 5GHz



Normalized SAR Limit	1.0
Max time-averaged Normalized SAR	0.281
Validated: Max time-averaged SAR is within device uncertainty of measured SAR at Plimit	

4.1.6. WLAN Dual Band Simultaneous (DBS)

Total Normalized Time-averaged RF Exposure
Tech: WLAN, Band 5GHz / Tech: WLAN, Band 2.4GHz

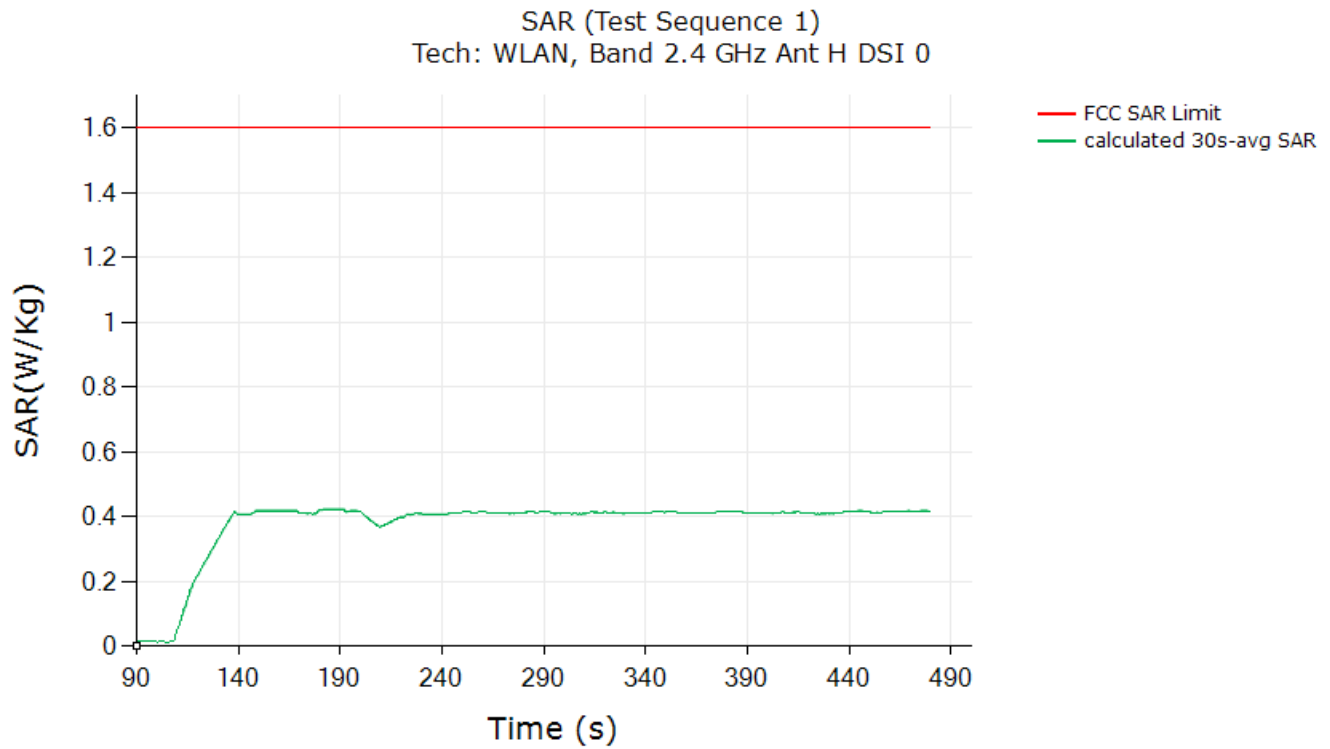


Normalized SAR Limit	1.0
Max time-averaged Normalized SAR	0.260
Validated: Max time-averaged SAR is within device uncertainty of measured SAR at Plimit	

4.2. Radiated SAR Cases (Freq < 6 GHz)

4.2.1. 2.4 GHz WLAN 802.11n

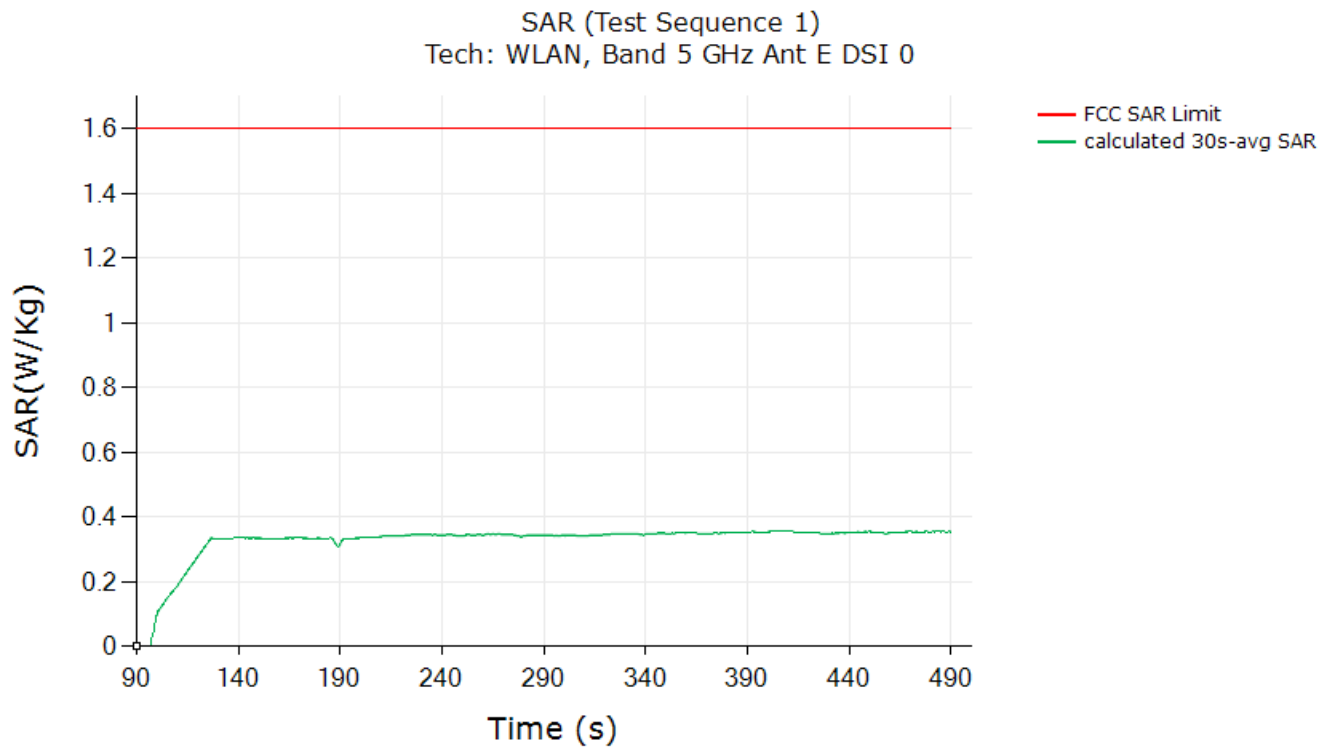
Test Sequence A



	W/kg
FCC SAR Limit	1.6
Max 30 sec time-averaged 1g SAR	0.423
Validated: Max time-averaged SAR is within device uncertainty of measured SAR at Plimit	

4.2.2. 5 GHz WLAN 802.11ac

Test Sequence A



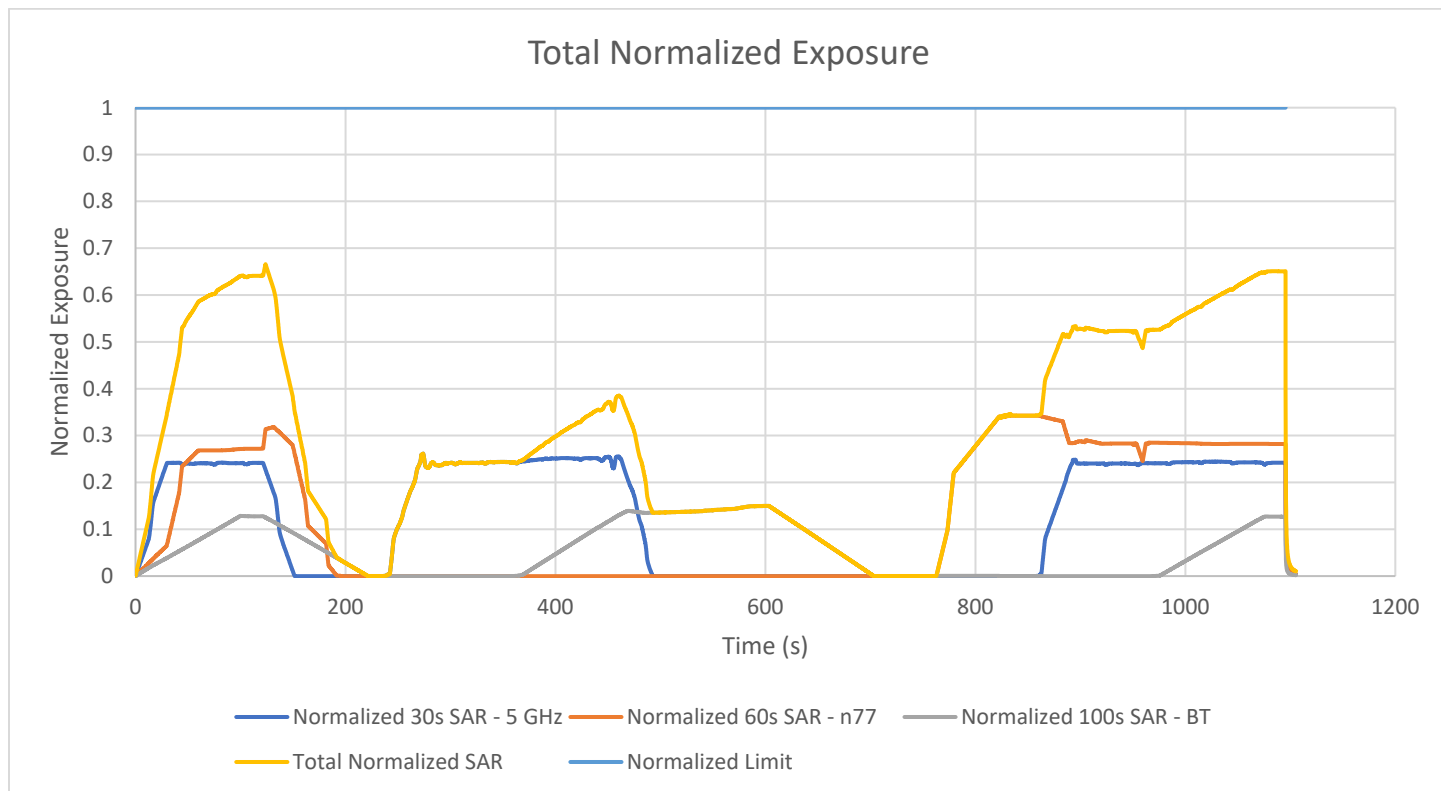
	W/kg
FCC SAR Limit	1.6
Max 30 sec time-averaged 1g SAR	0.357
Validated: Max time-averaged SAR is within device uncertainty of measured SAR at Plimit	

5. S.LSI and Qualcomm FastConnect Part 2 Test Results

5.1. Conducted Tx Cases (Freq < 6 GHz)

Time-averaged conducted tx power is converted into time-averaged 1g SAR in the figures below. Please see below for time-averaged 1g SAR and SAR limit that the test result complies. Section 2 contains detailed information regarding the test configurations.

5.1.1. C-TAS (NR – WLAN – BT)



Normalized SAR Limit	1.0
Max time-averaged Normalized SAR	0.666
Validated: Max time-averaged SAR is within device uncertainty of measured SAR at Plimit	

6. Background on Radiofrequency (RF) Exposure Limits

6.1. Controlled Environment

Controlled environments are defined as locations where the RF field intensities have been adequately characterized by means of measurement or calculation and exposure is incurred by persons who are: aware of the potential for RF field exposure, cognizant of the intensity of the RF fields in their environment, aware of the potential health risks associated with RF field exposure and able to control their risk using mitigation strategies. In general, occupational/controlled exposure limits are applicable to situations in which persons are exposed as a consequence of their employment, who have been made fully aware of the potential for exposure and can exercise control over their exposure. This exposure category is also applicable when the exposure is of a transient nature due to incidental passage through a location where the exposure levels may be higher than the general population/uncontrolled limits, but the exposed person is fully aware of the potential for exposure and can exercise control over his or her exposure by leaving the area or by some other appropriate means.

6.2. Uncontrolled Environment

Uncontrolled environments are defined as locations where either insufficient assessment of RF fields have been conducted or where persons who are allowed access to these areas have not received proper RF field awareness/safety training and have no means to assess or, if required, to mitigate their exposure to RF fields. The general population/uncontrolled exposure limits are applicable to situations in which the general public may be exposed, or in which persons who may not be made fully aware of the potential for exposure, or cannot exercise control over their exposure. Members of the general public would fall under this category when exposure is not employment-related; for example, in the case of a wireless transmitter that exposes persons in its vicinity.

6.3. RF Exposure Limits for 100kHz – 6 GHz

Per FCC 47 CFR §1.1310, the SAR limits are applied for frequencies 100kHz ~ 6 GHz as shown below.

Table 6-1
Human Exposure to RF Radiation Limits FCC 47 CFR §1.1310 - SAR Basic Restrictions

Environment	Condition	SAR	Averaging volume
Uncontrolled / General Population	Head, Neck Trunk	1.6 W/kg	1g cube
	Extremity	4.0 W/kg	10g cube
Controlled	Head/Trunk	8 W/kg	1g cube
	Extremity / Limbs	20 W/kg	10g cube

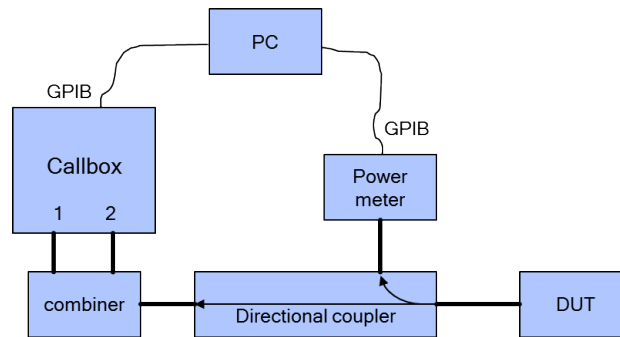
7. Technology Specific Test Setup Requirements

7.1. Measured and Reported SAR

When SAR is not measured at the maximum power level allowed for production units, the results must be scaled to the maximum tune-up tolerance limit according to the power applied to the individual channels tested to determine compliance. For simultaneous transmission, the measured aggregate SAR must be scaled according to the sum of the differences between the maximum tune-up tolerance and actual power used to test each transmitter. When SAR is measured at or scaled to the maximum tune-up tolerance limit, the results are referred to as *reported SAR*.

7.2. Conducted Power Measurement Test Setup

Callbox and power meter are connected to the test PC and test scripts are custom made for automation. Power meter readings are periodically recorded every 0.1s for sub6 technologies. A running average of this measured Tx power over the time-averaging window is performed in the post-data processing to determine the time-averaged power.



To demonstrate compliance, all the conducted tx power measurement results were converted into 1g_or_10gSAR values by using the equation listed below:

$$1g_or_10gSAR(t) = \frac{conducted_Tx_power(t)}{conducted_Tx_power_Plimit} * 1g_or_10gSAR_Plimit$$
$$\frac{\frac{1}{T_{SAR}} \int_{t-T_{SAR}}^t 1g_or_10gSAR(t) dt}{FCC\ SAR_{limit}} \leq 1$$

7.3. Test Procedures for Conducted Power Measurements (WWAN)

This section provides general conducted power measurement procedures to perform compliance test under dynamic transmission scenarios. The below figure provides an illustration of how the time-averaged power is calculated to determine the rolling average.

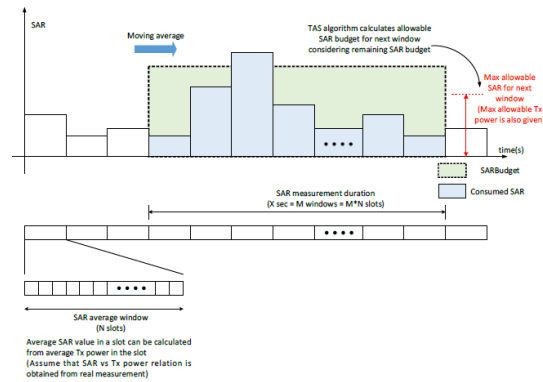


Figure 7-1
Time-averaging illustration

The RF exposure is proportional to transmit (Tx) power for SAR characterization. Accordingly, SAR feature validation can be effectively performed using conducted measurements, since SAR can be derived from transmit power levels. As a result, compliance demonstration under dynamic transmission conditions and TAS feature validation are conducted using a conducted power measurement setup for the defined transmission scenarios.

To provide additional confidence in this approach, the linear relationship between measured SAR and Tx power is demonstrated in the SAR Part 1 report.

1. Measurement of Transmit Power:

- Measure the conducted transmit power over time, denoted as $TxPower(t)$.
- All measurements are referenced to the UE antenna planes.
- Convert the measured powers to RF exposure values using a linear relationship:

$$SAR_{inst}(t) = TxPower(t) / P_{limit} \times SAR_design_target$$

Here, P_{limit} and are the *measured powers* at which the corresponding technology meets the SAR_design_target.

2. Calculate the Total RF Exposure:

- Calculate the total RF exposure over the most recent measurement durations for each RAT:
- The total exposure within a measurement duration is obtained by summing the instantaneous SAR values across all relevant RATs and bands for all time instances u within the respective intervals: $[t - T_{SAR}, t]$.

7.4. WWAN and C-TAS Test cases

To validate the time averaging feature and demonstrate the compliance in Tx varying transmission conditions, the following transmission scenarios are covered in the Part 2 test:

1. **Time-varying transmit power:** Verification that the TAS feature accurately accounts for transmit (Tx) power variations over time.
2. **Call disconnected and re-establishment:** Verification that the TAS feature correctly accounts for historical Tx power following call termination and subsequent re-establishment.
3. **RSI (Radio SAR Index) change:** Verification that the TAS feature operates correctly and maintains compliance limits across RSI changes.
4. **Technology/band/antenna handover:** Verification that the TAS feature correctly maintains and applies Tx power history across band and RAT transitions.
5. **Uplink Carrier Aggregation (UL CA):** Verification that the TAS feature correctly handles component carrier (CC) addition and removal, supporting both single-CC and CA operation.
6. **SAR exposure switching:** Verification that the TAS feature supports multi-RAT transmission with transitions in operating modes.
7. **NSA with antenna switching:** Verification that the TAS feature correctly handle the change of NSA antenna switching with both active RATs operating simultaneously.
8. **Spatial TAS operation:** Verification of TAS operation with uncoupled antennas under dual-transmitter scenarios. Note that, for scenarios involving two simultaneous transmitters, coupling cases shall be evaluated to demonstrate compliance with SAR regulatory requirements, while uncoupling cases may be evaluated on an optional basis.
9. **WWAN + WLAN + BT:** To demonstrate the time averaged RF exposure compliance continuity during technology transition in both single-radio and multi-radio transmission scenarios and under both modes (i.e., ON and airplane).

7.4.1. Time-varying Tx power scenario

Two predefined time-varying transmit (Tx) power sequences are applied for all RAT cases, as described below:

1. **Test Sequence A:** This sequence consists of two power levels. One level is the maximum transmit power, P_{max} , which is applied for at least 150 seconds. The other level is set to the target power level plus 2 dB ($P_{limit}(\text{dBm}) + 2 \text{ dB}$) and is applied for at least 200 seconds.
2. **Test Sequence B:** This sequence consists of multiple transmit power levels. The specific power levels are defined in Table 7-2 as functions of P_{max} and P_{limit} .

Table 7-2
Test Sequence B

Time [Sec]	Definition
15	$P_{limit} - 5$
20	P_{limit}
20	$P_{limit} + 5$
10	$P_{limit} - 6$
20	P_{max}
15	P_{limit}
15	$P_{limit} - 7$
20	P_{max}
10	$P_{limit} - 5$
15	P_{limit}
10	$P_{limit} - 6$
20	$P_{limit} + 5$
10	$P_{limit} - 4$
15	P_{limit}
10	$P_{limit} - 6$
20	P_{max}
15	$P_{limit} - 8$
15	P_{limit}
20	P_{max}
10	$P_{limit} - 9$
20	$P_{limit} + 5$
20	P_{limit}
15	$P_{limit} - 5$

The Samsung S.LSI TAS algorithm operates independently of band, mode, or channel for a given technology. Accordingly, validation can be performed using one or two representative band/mode/channel combinations per technology. The selection of these combinations is based on the relative values of P_{limit} and P_{max} .

Specifically, the selected combination must satisfy $P_{limit} < P_{max}$ so that the TAS algorithm actively enforces transmit power restrictions.

This test is performed using the two predefined test sequences for all sub-6 GHz technologies, including GSM, WCDMA, LTE, and NR FR1. The purpose of the test is to demonstrate enforcement of maximum transmit power limits and to verify that the time-averaged SAR always remains below the FCC limit.

Test procedure

1. Using P_{max} and P_{limit} , generate the power level test sequences for each selected technology and band. Both Test Sequences A and B are generated. Maximum power may be adjusted based on DUT test results.
2. Connect the DUT to the call box in the selected RAT. Configure the call box to request DUT transmit power according to the sequences generated in Step 1. Set an initial transmit power of 0 dBm for 60 seconds prior to starting the test sequence to facilitate post-processing of the time-averaged values with the first sequence value.
3. After completion of the sequence, release the connection.
4. Plot Instantaneous and Averaged Power
 - Instantaneous transmit power versus time (measured in Step 2)
 - Requested transmit power versus time (from Step 2)
 - Time-averaged power over 60 seconds using instantaneous values from Step 2
 - P_{limit} determined to meet the SAR design target
5. Plot Time-Averaged SAR
 - Computed time-averaged 1 g SAR versus time (from Step 2)
 - FCC 1 g SAR limit of 1.6 W/kg

7.4.2. Change in Call Scenario

The criterion for selecting the technology and band for call setup and call drop transition testing is to choose the band with the lowest P_{limit} among all supported bands. The test is performed with the DUT requesting transmission at P_{max} so that the Samsung S.LSI TAS feature enforces transmit power restriction for the longest possible duration. The call transition is initiated while the DUT is operating under power-restricted conditions.

A single test is sufficient, as the TAS behavior is independent of band or technology. For the purpose of demonstrating TAS algorithm performance in this report, only the low P_{limit} case is considered.

This test is designed to demonstrate that the Samsung S.LSI TAS feature correctly accounts for historical transmit power values during time averaging when a new call is established. The call transition is performed while the DUT is operating under active power-limit enforcement.

Test procedure

1. Connect the DUT to the call box.
2. Configure the call box to set DUT transmit power to a low value below 0 dBm for 60 seconds.
3. Configure the call box to send "ALL UP" power control commands.
4. Continue transmission from the DUT to achieve the maximum power P_{max} .
5. After 150 seconds of transmission at P_{max} , release the call from the call box.
6. After 10 seconds, re-establish the LTE connection from the call box to the DUT.
7. Repeat sending "ALL UP" power control commands to bring transmit power to P_{max} and continue transmission for 140 seconds.
8. Release the LTE connection at the end of the sequence.
9. Plot Instantaneous and Averaged Power
 - Instantaneous transmit power versus time (measured in Step 2)
 - Requested transmit power versus time (from Step 2)
 - Time-averaged power over 60 seconds using instantaneous values from Step 2
 - P_{limit} determined to meet the SAR design target
10. Plot Time-Averaged SAR
 - Computed time-averaged 1 g SAR versus time (from Step 2)
 - FCC 1 g SAR limit of 1.6 W/kg

The current TAS algorithm software enables the UE to accurately estimate transmit power and time-averaged SAR, even during call drop and call re-establishment events. The UE records the time when it enters sleep mode and uses this information upon wake-up to calculate the durations of transmit power on and off periods

7.4.3. Change in Technology and Band and Antenna

FCC specifies different measurement durations for time averaging based on the operating frequency. The criterion for selecting test cases to demonstrate compliance is to choose a technology, band, and antenna group for which $P_{limit} < P_{max}$, ensuring that the TAS algorithm actively enforces transmit power restrictions.

For the purpose of demonstrating TAS algorithm performance in this report, only the low P_{limit} case is considered.

This test is designed to demonstrate that the Samsung S.LSI TAS feature can correctly handle changes in technology, band, and antenna when a new event occurs. Since both P_{limit} and the antenna can vary across bands, separate equations are used to convert transmit power to SAR, and combined SAR exposure criteria are applied as follows:

$$SAR_1(t) = TxPower_1(t) / P_{limit,1,FR1} \times SAR_{design\ target1}$$

$$SAR_2(t) = TxPower_2(t) / P_{limit,2,FR1} \times SAR_{design\ target2}$$

Here:

- $P_{limit,1,FR1}$ corresponds to the measured power at which the first technology/band meets the measured SAR level of $SAR_{design\ target1}$, with a time-averaging duration of $T_{1,SAR}$.
- $P_{limit,2,FR1}$, $SAR_{design\ target2}$, and $T_{2,SAR}$ are similarly defined for the second technology/band/antenna combination.
- In this report, a 60-second time-averaging duration is applied for all sub-6 GHz bands, including those below 3 GHz.

Test procedure

1. Establish radio connection of DUT with call box.
2. Configure call box to set DUT Tx power to a low value below 0 dBm for 60s.
3. Configure call box to send "ALL UP" power control commands and continue transmission from DUT so that maximum power of P_{max} is achieved Continue the transmission for 150s.
4. Change the technology/band/antenna to 2nd technology/band/antenna and continue the transmission for another 150s.
5. Release the connection.
6. Plot Instantaneous and Averaged Power
 - Instantaneous transmit power versus time (measured in Step 2)
 - Requested transmit power versus time (from Step 2)
 - Time-averaged power over 60 seconds using instantaneous values from Step 2
 - P_{limit} determined to meet the SAR design target
7. Plot Time-Averaged SAR
 - Computed time-averaged 1 g SAR versus time (from Step 2)
 - FCC 1 g SAR limit of 1.6 W/kg

It is required to check if power limiting enforcement is operated as expected when tech/band/antenna change occurs in between.

7.4.4. Change in RSI

The criterion for selecting a test case to demonstrate compliance across an RSI change within a radio is to choose a technology and band for which $P_{limit} < P_{max}$ in both RSI states. This ensures that the TAS algorithm actively enforces transmit power restrictions in each state.

For the purposes of demonstrating TAS algorithm performance in this report, only the low P_{limit} case is considered.

This test is designed to demonstrate that the Samsung S.LSI TAS feature can correctly handle changes in the RSI resulting from different SAR index states detected by the host platform software. The test involves modifying

Test procedure

1. Establish radio connection of DUT with call box.
2. Configure call box to set DUT Tx power to a low value below 0 dBm for 60s and set the RSI index for 1st RSI.
3. Configure call box to send "ALL UP" power control commands and continue transmission from DUT so that maximum power of P_{max} is achieved Continue the transmission for 150s.
4. Change the RSI index to 2nd RSI and continue the transmission for another 150s.
5. Release the connection.
6. Plot Instantaneous and Averaged Power
 - Instantaneous transmit power versus time (measured in Step 2)
 - Requested transmit power versus time (from Step 2)
 - Time-averaged power over 60 seconds using instantaneous values from Step 2
 - P_{limit} determined to meet the SAR design target
7. Plot Time-Averaged SAR

- Computed time-averaged 1 g SAR versus time (from Step 2)
- FCC 1 g SAR limit of 1.6 W/kg

It is required to check if power limiting enforcement is operated as expected when RSI index is changed during the test.

7.4.5. Uplink CA

The criterion for selecting this test case is to demonstrate TAS algorithm compliance during LTE/NR transmission with multiple component carriers (CCs). This test verifies that TAS algorithm compliance is independent of the transmission scenario, whether operating with a single CC or with carrier aggregation (CA).

This test is designed to demonstrate that the Samsung S.LSI TAS feature can correctly manage SAR exposure during LTE/NR transmission when additional intra-band or inter-band LTE/NR component carriers (CCs) are added or removed.

Test procedure

1. Establish radio connection of DUT with call box over cell 1.
2. Configure call box to set DUT Tx power to a low value below 0 dBm for 60s.
3. Configure call box to send "ALL UP" power control commands and continue transmission from DUT so that maximum power of P_{max} is achieved Continue the transmission for 150s.
4. Establish connection of DUT with call box over Cell 2, other cell of the band Combo CA and continue the transmission for another 150s.
5. Release the connection.
6. Plot Instantaneous and Averaged Power
 - Instantaneous transmit power versus time (measured in Step 2)
 - Requested transmit power versus time (from Step 2)
 - Time-averaged power over 60 seconds using instantaneous values from Step 2
 - P_{limit} determined to meet the SAR design target
7. Plot Time-Averaged SAR
 - Computed time-averaged 1 g SAR versus time (from Step 2)
 - FCC 1 g SAR limit of 1.6 W/kg

It is required to check if power limiting enforcement is operated as expected when intra-band or inter-band change occurs.

7.4.6. SAR Exposure Switching

The criterion for selecting this test case is to choose one LTE band and one NR band for which $P_{limit} < P_{max}$ in each case. The test is performed with both RATs operating simultaneously in an EN-DC scenario.

These tests are designed to demonstrate that the Samsung S.LSI TAS feature can correctly handle changes in the dominant SAR-contributing radio when two RATs are active simultaneously. The test involves adjusting the required transmit power of both radios so that either one or both RATs become the dominant contributor to the total exposure ratio at different times during the test.

Test procedure:

1. Connect the DUT to both LTE and NR call boxes in an NSA.
2. Configure both LTE and NR call boxes to set DUT transmit power to a low value of 0 dBm for 60 seconds.
3. Configure the NR call box to send "ALL UP" power control commands.
4. Continue DUT transmission until NR reaches maximum P_{max} and maintain for 150 seconds.
5. Configure the LTE call box to send "ALL UP" power control commands, resulting in both LTE and NR requesting maximum power from the DUT.
6. Continue transmission for 150 seconds.
7. Configure the NR call box to send "ALL DOWN" power control commands so that LTE becomes the dominant SAR-contributing radio.
8. Continue transmission for 150 seconds.
9. Release both LTE and NR connections.
10. Plot Instantaneous and Averaged Power
 - Instantaneous transmit power versus time (measured in Step 2)
 - Requested transmit power versus time (from Step 2)
 - Time-averaged power over 60 seconds using instantaneous values from Step 2
 - P_{limit} determined to meet the SAR design target
11. Plot Time-Averaged SAR
 - Computed time-averaged 1 g SAR versus time (from Step 2)
 - FCC 1 g SAR limit of 1.6 W/kg

It is required to check if power limiting enforcement is operated as expected when dominant power is changed in ENDC.

7.4.7. NSA Antenna Switching

The criterion for selecting this test case is to choose one LTE band and one NR band for which $P_{limit} < P_{max}$ in each case. The tests are performed with both RATs operating simultaneously, either in an EN-DC scenario or in a dual-SIM scenario with various power-sharing (pre-saving) configurations.

This test is designed to demonstrate that the Samsung S.LSI TAS feature can correctly handle antenna switching in an NSA configuration with two simultaneous active RATs. The test involves changing the transmit antennas of both radios so that either one or both RATs become the dominant contributor to the total exposure ratio at different times during the test.

Test procedure:

1. Connect the DUT to both LTE and NR call boxes in an NSA configuration.
2. Configure both LTE and NR call boxes to set DUT transmit power to a low value of 0 dBm for 60 seconds.
3. Configure the LTE call box to send "ALL UP" power control commands. Continue DUT transmission until LTE reaches maximum power P_{max} and maintain for 150 seconds.
4. Configure the NR call box to send "ALL UP" power control commands, resulting in maximum power requests from the DUT for both LTE and NR. Continue transmission for 150 seconds.
5. Change NR from 1st antenna to 2nd antenna. Configure the NR call box to send "ALL UP" power control commands and continue transmission for 150 seconds.
6. Release both LTE and NR connections.
7. Plot Instantaneous and Averaged Power
 - Instantaneous transmit power versus time (measured in Step 2)
 - Requested transmit power versus time (from Step 2)
 - Time-averaged power over 60 seconds using instantaneous values from Step 2
 - P_{limit} determined to meet the SAR design target
8. Plot Time-Averaged SAR
 - Computed time-averaged 1 g SAR versus time (from Step 2)
 - FCC 1 g SAR limit of 1.6 W/kg

It is required to check if power limiting enforcement is operated as expected when Tx antenna is changed in ENDC.

7.4.8. C-TAS - WWAN + WLAN + BT

Below is the test flow outline of the C-TAS. The test contains 9 sections and 8 transitions:



1. Airplane Mode OFF : CP ON ,WLAN ON ,BT ON
2. Airplane Mode ON : CP OFF, WLAN OFF, BT : OFF
3. Airplane Mode ON : WLAN ON , CP OFF, BT,OFF
4. Airplane Mode ON : WLAN ON , BT ON , CP OFF
5. Airplane Mode ON : WLAN OFF , BT ON , CP OFF
6. Airplane Mode ON : WLAN OFF , BT OFF, CP OFF
7. Airplane Mode OFF : CP ON, BT OFF, WLAN OFF
8. Airplane Mode OFF : CP ON, WLAN ON , BT OFF
9. Airplane Mode OFF : CP ON ,WLAN ON ,BT ON

Plot Time-Averaged SAR

- RF Exposure of External Radio represents the worst-case measured SAR of non-TAS radios reported in the RF Exposure Part 1 Report (e.g., WPT, NFC, etc.) is 0.021 W/kg.
- Computed time-averaged 1g SAR versus time, FCC 1 g SAR limit of 1.6 W/kg.
- Computed normalized time-averaged 1g SAR versus time, FCC normalized SAR limit of 1.0.

Note: WWAN Mode = CP

Through this technology switching compliance test, the CP (WWAN Mode), WLAN, and BT modes were evaluated under simultaneous transmission conditions with each technology actively transmitting together. During the simultaneous transmission state of each technology mode on the DUT, the output power is monitored and controlled by the C-TAS algorithm. The results confirm that the DUT complies with the applicable FCC regulatory exposure limits.

7.5. Test Procedures for Conducted Power Measurements (WLAN)

Since RF exposure is proportional to the Tx power for a SAR wireless device, time-averaging algorithm validation can be effectively performed through conducted power measurements outlined below.

Time-Varying Test Sequence: This test proves the FastConnect TAS accounts for Tx power variations in time accurately. In addition, this test is performed to capture the maximum time-averaged results in at least two time-averaging windows duration.

1. **Change in antenna (applicable when the software supports SISO diversity operation):** This test is to prove that FastConnect functions correctly during transitions in Plim (at different antennas) within the same WLAN band and same Antenna Group. If device supports SISO and transmission diversity between an Antenna to another antenna, then this test is applicable. If WLAN MIMO CDD is implemented, then device is always under MIMO transmission, in this case, this test is NOT applicable.
2. **Change in device state (DSI) (applicable when the device supports multiple DSI):** This is to prove that FastConnect TAS performs power enforcements to maintain compliance during transitions in the device state.
3. **Change in WLAN band:** This is to prove that the FastConnect TAS functions correctly during transitions in radios and bands.
4. **Simultaneous Transmission:** This is to prove that the FastConnect TAS functions in transition from 1st standalone WLAN radio to simultaneous WLAN radios and back to 2nd standalone WLAN radio.

To add confidence in the feature validation, the time-averaged SAR measurements are also performed but only performed for transmission scenario 1 to avoid the complexity in SAR (such as, for scenario 3 requiring change in SAR probe calibration file to accommodate different bands and/or tissue simulating liquid).

The strategy for testing in Tx varying transmission condition is outlined as follows:

- Demonstrate the total RF exposure averaged over FCC defined time windows does not exceed FCC's SAR limits, through time-averaged power measurements:
 - o Measure conducted power.
 - o Convert it into RF exposure and divide by respective limits to get normalized exposure use equation as described in this section.
 - o Perform time-averaging over predefined time windows.
 - o Demonstrate that the total normalized time-averaged RF exposure is <1 for all transmission scenarios.
- Demonstrate the total RF exposure averaged over FCC defined time windows does not exceed FCC's SAR limits, through time-averaged SAR measurements. Note as mentioned earlier, this measurement is performed for transmission scenario 1 only.
 - o Choose worst case EUT orientation of SAR measurement per according to Static SAR test report and perform pointSAR measurement

- o Measure instantaneous SAR versus time and demonstrate total normalized time-averaged exposure is <1.0 at all times

7.5.1. Time-Varying Test Sequence

Select one representative test channel from all the available radio configurations (band/ant(s)/DSI) that has $P_{max} > P_{lim} + \text{device uncertainty}$.

1. If the device supports SISO, then SISO is preferred over MIMO due to simplified test setup.
2. After determining SISO vs. MIMO configuration, then select the configuration that has largest ($P_{max} \text{ dBm} - P_{lim} \text{ dBm}$) dB delta.
 - If $P_{max} < P_{lim} + \text{device uncertainty}$ for all radio configurations, then select radio configuration with largest ($P_{max} \text{ dBm} - P_{lim} \text{ dBm}$) value.
 - Test to be performed at two bands for Time-Varying Test sequence test.
 - If only one band within a configuration has $P_{max} > P_{lim}$ in all other configurations, then only one band needs to be tested.
 - Test is not required if $P_{lim} > P_{max}$ for all radio configurations.

NOTE: The same selection criteria are applicable for both conducted & radiated tests.

7.5.2. Change in Antenna

This test scenario does not apply if SISO mode diversity is not supported. (e.g. CDD is enabled and always use MIMO).

The criteria to select test configuration for Change in Antenna measurement is:

- The antennas selected for this test should be in the same antenna group.
- Whenever possible and supported by the EUT, first select antenna switch configuration within the same band/DSI (i.e., same band and DSI combination), and having different P_{lim} , and having both $P_{max} > P_{lim} + \text{device uncertainty}$ where possible. Otherwise, select at least one antenna having $P_{max} > P_{lim} + \text{device uncertainty}$.
 - o If multiple radio configurations (band/DSI) meet $P_{max} > P_{lim} + \text{device uncertainty}$, then select the configuration that has largest ($P_{max} \text{ dBm} - P_{lim} \text{ dBm}$) dB delta.
 - o If $P_{max} < P_{lim} + \text{device uncertainty}$ for all radio configurations, then select radio configuration with largest ($P_{max} \text{ dBm} - P_{lim} \text{ dBm}$) value.
 - o If the EUT does not support antenna switch within the same band but has multiple transmitting antennas to support different frequency bands, then antenna switch test should be performed in combination with Change in WLAN band test scenario.
- Test for Change in Antenna is not required if $P_{lim} > P_{max}$ for all radio configurations.

7.5.3. Change in Device State Index (DSI)

This test scenario does not apply if multiple DSIs is not supported in the device. The criteria to select test configuration for Change in DSI measurement is:

- Select a band/antenna having the $P_{\max} > P_{\text{lim}} + \text{device uncertainty}$ within any DSI, and for the same band/antenna(s) having a different P_{lim} in any other DSI. Both the selected DSIs should have $P_{\max} > P_{\text{lim}} + \text{device uncertainty}$ where possible. Otherwise, select at least one DSI having $P_{\max} > P_{\text{lim}} + \text{device uncertainty}$.
- If $P_{\max} < P_{\text{lim}} + \text{device uncertainty}$ for all band/antenna(s), then select radio configuration with largest $(P_{\max} \text{ dBm} - P_{\text{lim}} \text{ dBm})$ value.
- If $P_{\max} > P_{\text{lim}} + \text{device uncertainty}$ for more than one radio configuration, then order of preference is given by:
 - If multiple radio configurations (band/ant(s)/DSI) meet this criteria and if device support SISO. Then SISO is preferred over MIMO due to simplified test setup.
 - After determining SISO vs. MIMO configuration, then select the configuration that has largest $(P_{\max} \text{ dBm} - P_{\text{lim}} \text{ dBm})$ dB delta.

Test for Change in DSI is not required if all $P_{\text{lim}} > P_{\max}$ for all radio configurations.

7.5.4. Change in WLAN Band

The criteria to select test configuration for Change in WLAN band measurement is:

- First select both bands in a DSI having $P_{\max} > P_{\text{lim}} + \text{device uncertainty}$ where possible. Otherwise, select at least one band having $P_{\max} > P_{\text{lim}} + \text{device uncertainty}$.
- If $P_{\max} < P_{\text{lim}} + \text{device uncertainty}$ for all radio configurations, then select radio configuration with largest $(P_{\max} \text{ dBm} - P_{\text{lim}} \text{ dBm})$ value.
- If $P_{\max} > P_{\text{lim}} + \text{device uncertainty}$ for more than one radio configuration. Then, order of preference is given by:
 - If multiple radio configurations (band/ant(s)/DSI) meet this criteria and if device support SISO. Then SISO is preferred over MIMO due to simplified test setup.
 - After determining SISO vs. MIMO configuration, then select the configuration that has largest $(P_{\max} \text{ dBm} - P_{\text{lim}} \text{ dBm})$ dB delta.
- The antennas corresponding to the selected bands should be in the same antenna group.
- Test for Change in WLAN band is not required if all $P_{\text{lim}} > P_{\max}$ for all radio configurations.

7.5.5. Simultaneous Transmission (DBS)

This test scenario does not apply if simultaneous transmission within WLAN bands is not supported in the device. The criteria to select test configuration for Simultaneous Transmission measurement is:

- The bands must be selected from supported Simultaneous Transmission configuration. (e.g., WLAN DBS and/or HBS)
- First select both bands in a DSI having $P_{max} > P_{lim} + \text{device uncertainty}$ where possible. Otherwise, select at least one band having $P_{max} > P_{lim} + \text{device uncertainty}$.
- If $P_{max} < P_{lim} + \text{device uncertainty}$ for all radio configurations, then select radio configuration with largest $(P_{max} \text{ dBm} - P_{lim} \text{ dBm})$ value.
- If $P_{max} > P_{lim} + \text{device uncertainty}$ for more than one radio configuration. Then, order of preference is given by:
 - o If multiple radio configurations (band/ant(s)/DSI) meet this criteria and if device support SISO. Then SISO is preferred over MIMO due to simplified test setup.
 - o After determining SISO vs. MIMO configuration, then select the configuration that has largest $(P_{max} \text{ dBm} - P_{lim} \text{ dBm})$ dB delta.
- The antennas corresponding to the selected bands should be in the same antenna group.
- Even if a device has $P_{lim} > P_{max}$ for all radio configurations, then "Simultaneous Transmission" test scenario should still be performed for validation of FastConnect TAS device.

8. Equipment List

Manufacturer	Model	Description	Serial Number	Calibration Date	Calibration Due	CBT
Amplifier Research	551G4	RF Broadband Amplifier (800 MHz - 4.2 GHz)	331258	-	-	✓
Rohde & Schwarz	SMCV100B	R&S SMCV100B Vector Signal Generator (VSG)	103882	12/30/25	12/30/27	-
SPEAG	Powersource1	Signal Generator	4341	1/6/26	1/6/27	-
Anritsu	MA24118A	Microwave USB Power Sensor (10MHz - 18 GHz)	2123431	1/22/26	1/22/27	-
Anritsu	MA24118A	Microwave USB Power Sensor (10MHz - 18 GHz)	2123500	1/22/26	1/22/27	-
Rohde & Schwarz	NRP8S	Power Sensor 10 MHz - 8 GHz	114184	3/12/26	3/12/27	-
Rohde & Schwarz	NRP8S	Power Sensor 10 MHz - 8 GHz	114183	3/12/26	3/12/27	-
Rohde & Schwarz	NRP8S	Power Sensor 10 MHz - 8 GHz	114343	4/1/26	4/1/27	-
Anritsu	S820E	Vector Network Analyzer	2348026	1/13/26	1/13/28	-
Control Company	4040	Ambient Thermometer	250440190	7/17/25	7/17/27	-
Control Company	4040	Ambient Thermometer	250440191	7/17/25	7/17/27	-
Control Company	4040	Ambient Thermometer	250440199	7/17/25	7/17/27	-
Control Company	4352	Long Stem Liquid Thermometer	250257657	4/23/25	4/23/27	-
Control Company	4352	Long Stem Liquid Thermometer	250257660	4/23/25	4/23/27	-
Control Company	4352	Long Stem Liquid Thermometer	250257665	4/23/25	4/23/27	-
Micro-Coax	UFB205A-0-0240-30x30	SMA M-F RF Test Cable (DC - 18 GHz)	-	-	-	✓
Mini-Circuits	BW-N20W20+	20dB RF Fixed Attenuator (DC - 18 GHz)	-	-	-	✓
Mini-Circuits	BW-N20W20+	20dB RF Fixed Attenuator (DC - 18 GHz)	-	-	-	✓
Mini-Circuits	BW-S3W2+	3dB RF Fixed Attenuator (DC - 18 GHz)	-	-	-	✓
Mini-Circuits	BW-S3W2+	3dB RF Fixed Attenuator (DC - 18 GHz)	-	-	-	✓
Mini-Circuits	CBL-6FT-SMNM+	Precision Test Cable SMA/N (DC - 18 GHz)	3318	-	-	✓
Mini-Circuits	CBL-6FT-SMNM+	Precision Test Cable SMA/N (DC - 18 GHz)	3335	-	-	✓
Mini-Circuits	CBL-6FT-SMNM+	Precision Test Cable SMA/N (DC - 18 GHz)	3329	-	-	✓
Mini-Circuits	NF-SF50+	RF Adapter N Male to SMA Female (DC - 18 GHz)	-	-	-	✓
Mini-Circuits	VLF-3000+	Coaxial Low Pass Filter (DC - 3 GHz)	-	-	-	✓
Narda	24785-20	20 dB SMA Fixed Attenuator (DC - 4.0 GHz)	-	-	-	✓
Narda	4226-20 (26733)	20 dB SMA Directional Coupler (0.5 - 18 GHz)	201	-	-	✓
Mitutoyo	CD-4"AX	Digital Caliper	B23243217	8/28/25	8/28/27	-
SPEAG	DAK-12	DAK-12 Dielectric Probe	1194	10/10/25	10/10/26	-
SPEAG	DAK-3.5	DAK-3.5 Dielectric Probe	1349	8/5/25	8/5/26	-
Speag	D2450V2	D2450V2 System Validation Dipole	1112	11/15/24	11/15/26	-
SPEAG	DAE4ip	Data Acquisition Electronics with Integ. Power	1838	12/4/25	12/4/26	-
SPEAG	EX3DV4	SAR Measurement Probe	7857	12/9/25	12/9/26	-
SPEAG	SE UMS 171 E	MAIA Modulation and Interference Analyzer	1814	-	-	-
SPEAG	SE UMS 171 E	MAIA Modulation and Interference Analyzer	1817	-	-	-
SPEAG	SE UMS 176 C	ANT Wideband Communication Antenna	1579	-	-	-
SPEAG	SE UMS 176 C	ANT Wideband Communication Antenna	1601	-	-	-
SPEAG	D5GHzV2	5GHz System Validation Dipole	1396	11/15/2024	11/15/2026	-
Rohde & Schwarz	CMW500	CMW500 Radio Communication Test Station	165091	1/28/26	1/28/28	-
Rohde & Schwarz	CMX500	Radio Communication Test Station	101329	4/7/26	4/7/28	-
SPEAG	D2450V2	D2450V2 System Validation Dipole	1112	11/15/2024	11/15/2026	-

* Components calibrated before testing. Prior to testing, the measurement paths containing a cable, attenuator, coupler or filter were connected to a calibrated source (i.e. a signal generator, power sensor, or VNA) to determine the losses of the measurement path. The power meter offset was then adjusted to compensate for the measurement system losses. This level offset is stored within the power meter before measurements are made. This calibration verification procedure applies to the system verification and output power measurements. The calibrated reading is then taken directly from the power meter after compensation of the losses for all final power measurements.

9. Conclusion

The SAR evaluation indicates that the DUT is capable of compliance with the RF radiation exposure limits of the FCC, with respect to all parameters subject to this test. These measurements were taken to simulate the RF effects of RF exposure under worst-case conditions. Precise laboratory measures were taken to assure repeatability of the tests. The results and statements relate only to the item(s) tested.

Please note that the absorption and distribution of electromagnetic energy in the body are very complex phenomena that depend on the mass, shape, and size of the body, the orientation of the body with respect to the field vectors, and the electrical properties of both the body and the environment. Other variables that may play a substantial role in possible biological effects are those that characterize the environment (e.g. ambient temperature, air velocity, relative humidity, and body insulation) and those that characterize the individual (e.g. age, gender, activity level, debilitation, or disease). Because various factors may interact with one another to vary the specific biological outcome of an exposure to electromagnetic fields, any protection guide should consider maximal amplification of biological effects as a result of field-body interactions, environmental conditions, and physiological variables.